

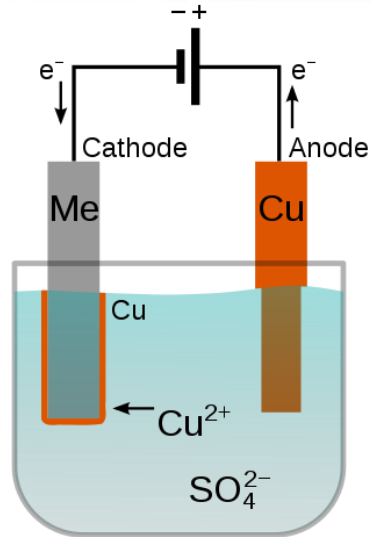
Copper Plating Research Activities for Cryocooler Application

Alena Prudnikava

InnovEEA Project Meeting

Wednesday 30 March 2022, 14:00 - 17:00 Europe/Berlin

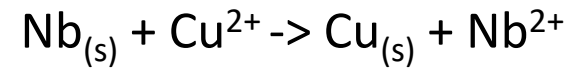
Copper Electroplating onto Niobium



For Cu-plating water-based acidic electrolytes are commonly used

Issues:

- Nb is an active metal: galvanic displacement reaction



Cu-film adhesion problem

Previously explored (reported in November):

- commercial acidic electrolytes for steel (uChem)
- several alkaline electrolytes for steel

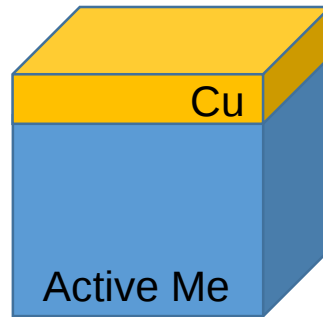
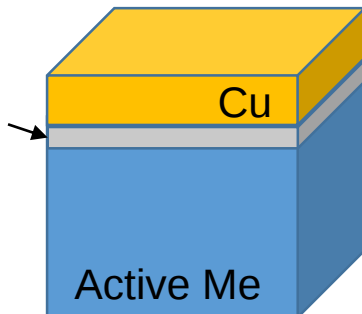
⇒ no good Cu-adhesion on Nb

⇒ modification of electrolyte composition, plating parameters...

Cu-plating onto
Active Metal

Alkaline Electrolyte
(worked for steel)

“less active” Me
(Ni, Sn...)



SEM

Cu film

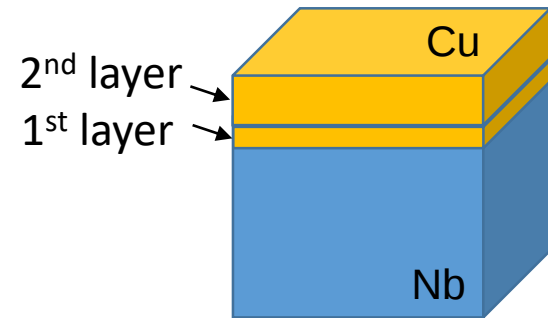
Cu film

- Cu film passed
- liquid nitrogen test
 - scotch-tape test



EDX

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Strategy:

1st Cu-layer (alkaline electrolyte): to be used as a buffer layer

2nd layer (acidic electrolyte): Cu-film of required thickness $n \cdot 100 \mu\text{m}$

Studying Cu-plating with Acidic Electrolyte

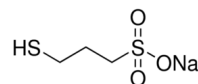
Electrolytes:

1. $\text{CuSO}_4/\text{H}_2\text{SO}_4/\text{H}_2\text{O}$
2. $\text{CuSO}_4/\text{H}_2\text{SO}_4$ with various additives (polyethylene glycol, sodium lauryl sulphate, benzotriazole)
3. $\text{CuSO}_4/\text{H}_2\text{SO}_4/\text{Cl}^-/\text{Janus Green B}/(\text{w/MPS or w/a MPS}^*)$
4. Commercial S.Aldrich Cu-plating solution

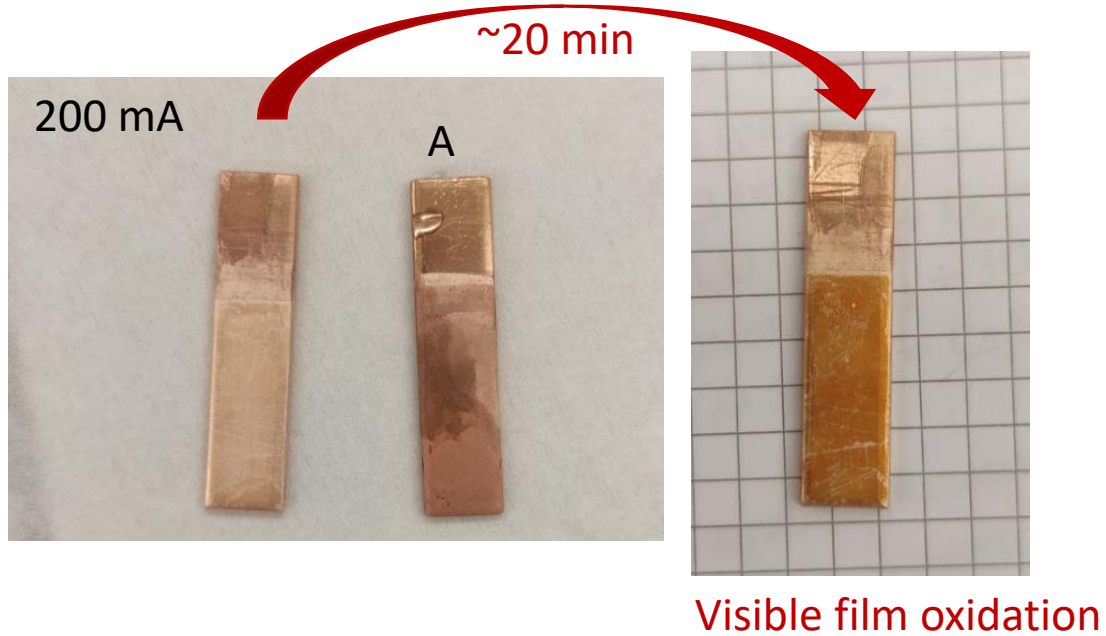
What was Studied:

1. Quality of Cu-films obtained using Standard Cupric Electrolyte (deposition rate: current density, temperature)
2. Influence of additives onto Cu-film oxidation (SEM/EDX, XRD)
3. Quality of films obtained using modified Cupric Electrolytes (deposition rate, uniformity, CuO_x)

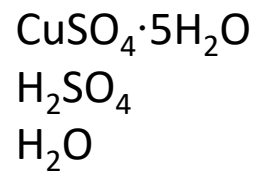
*MPS: Sodium 3-mercapto-1-propanesulfonate



Testing Acidic Electrolytes (1): Cu plating onto Copper

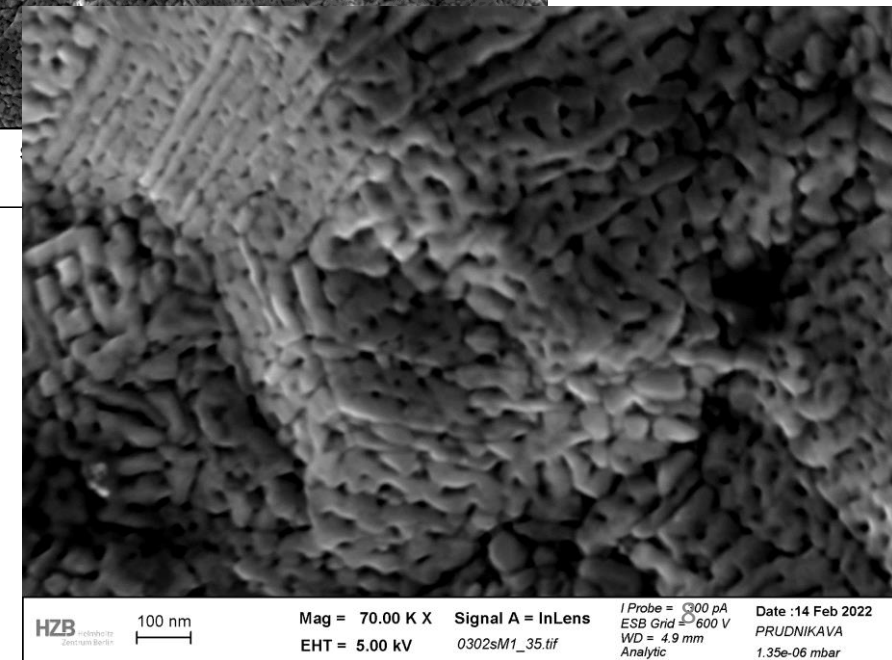
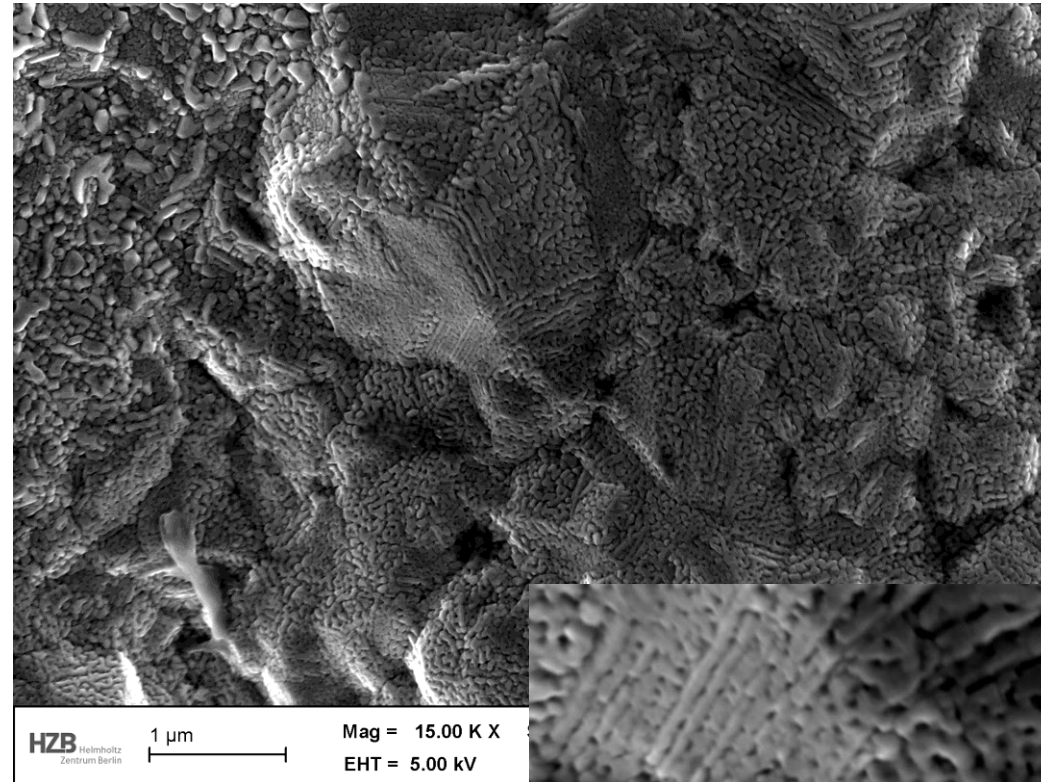


Electrolyte:

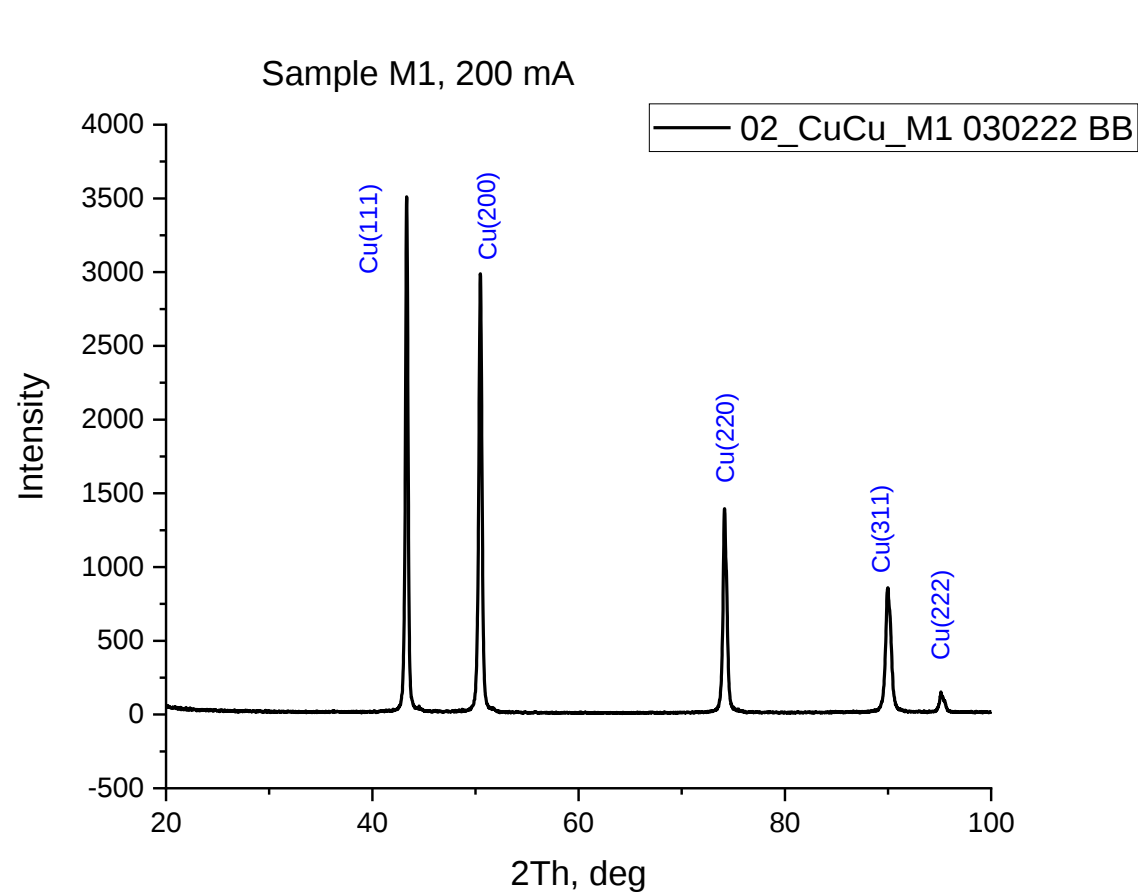


Plating parameters:

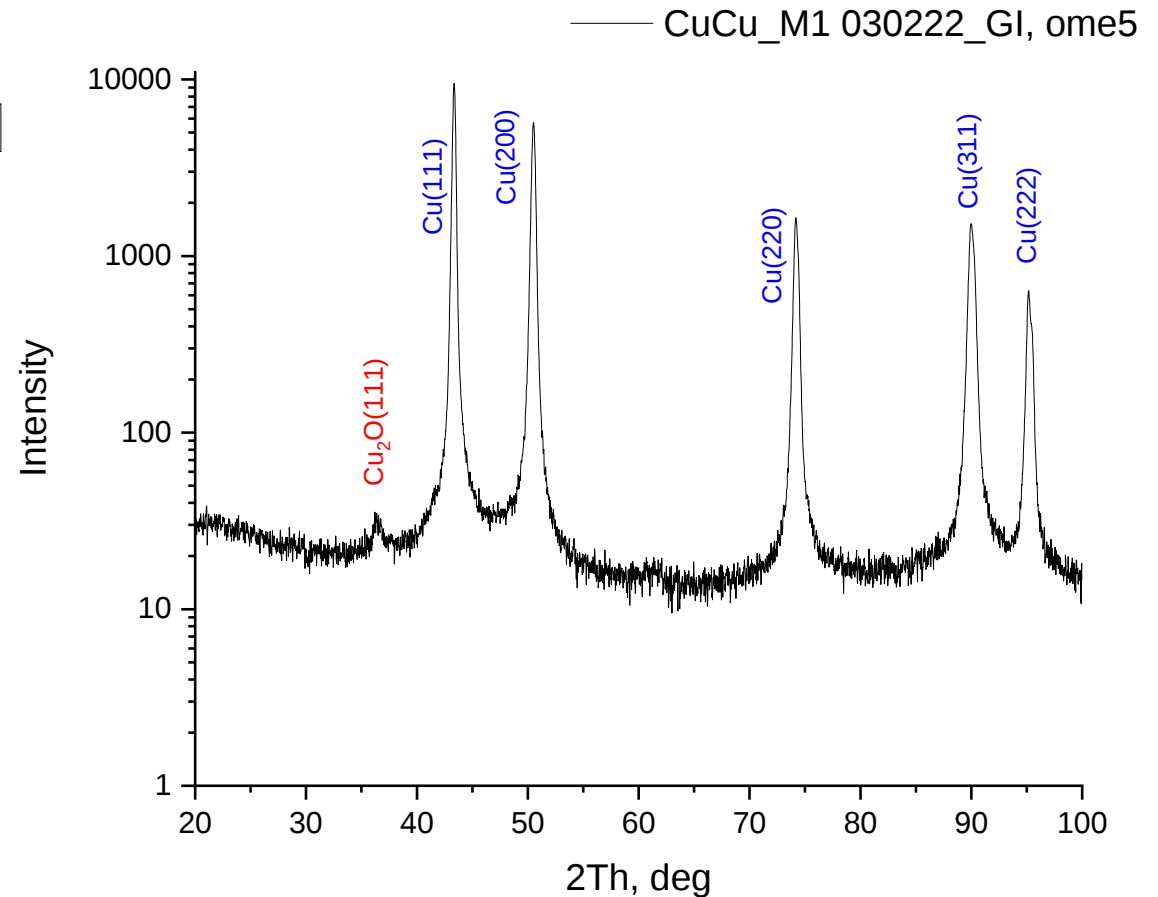
$j=2.7 \text{ A/dm}^2$
 $T=27^\circ\text{C}$
 $t=5 \text{ min}$



Testing Acidic Electrolytes (1): Cu plating onto Copper



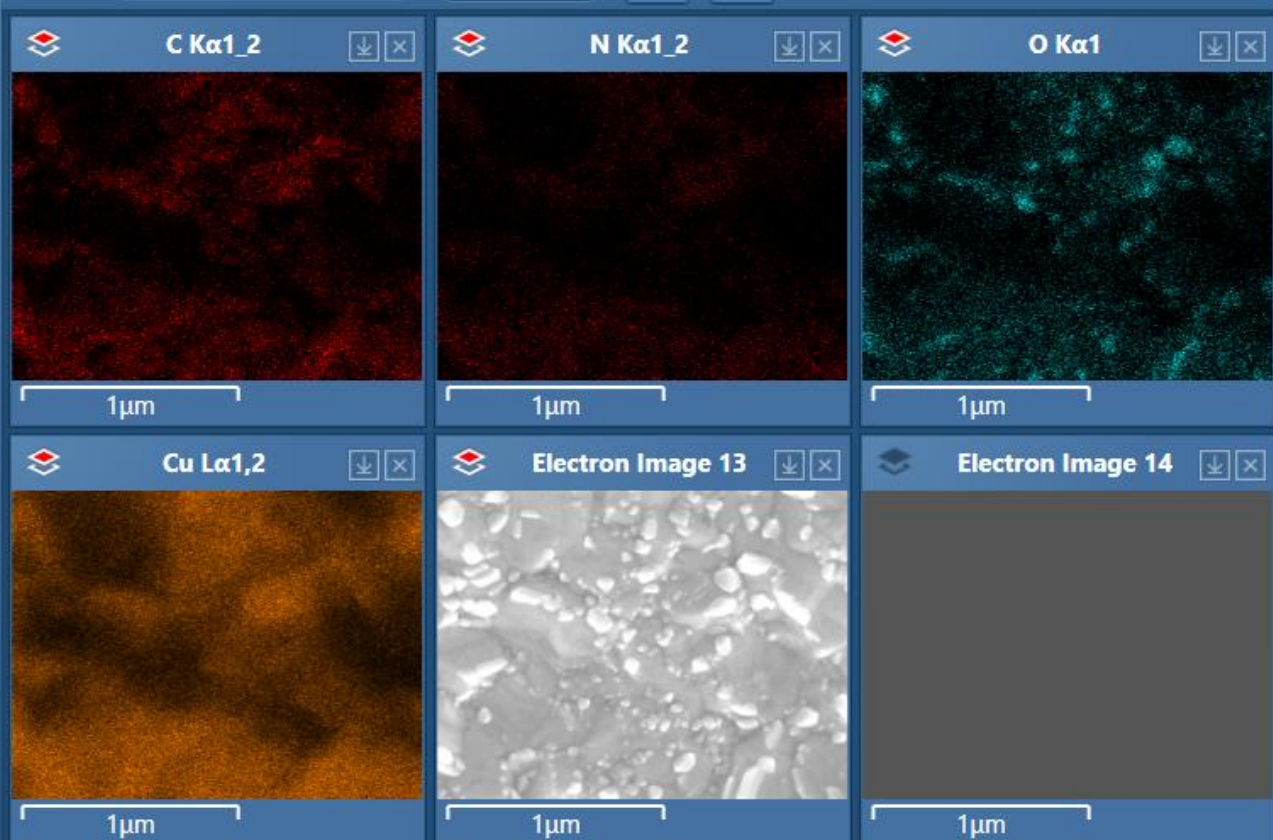
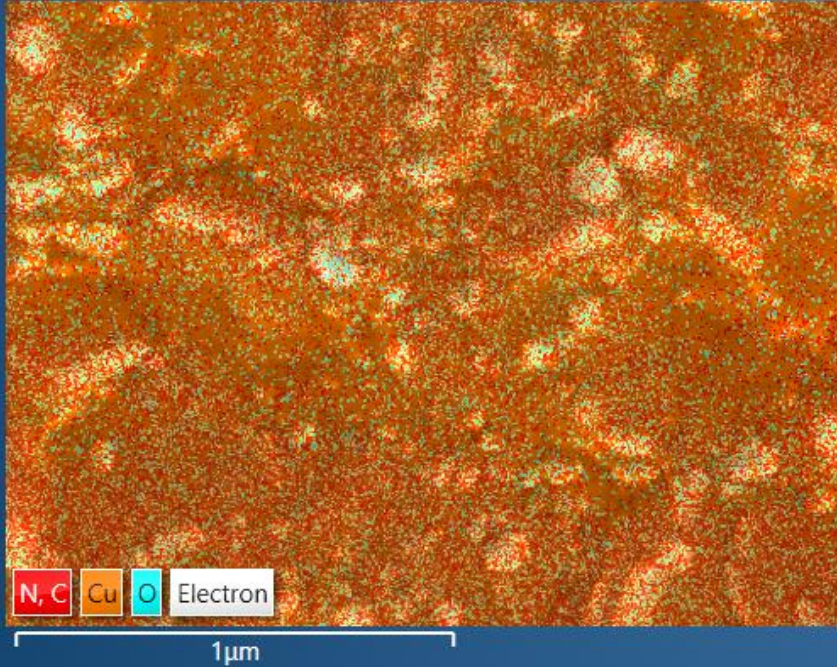
Cu(111), Cu(200) are the preferential orientations



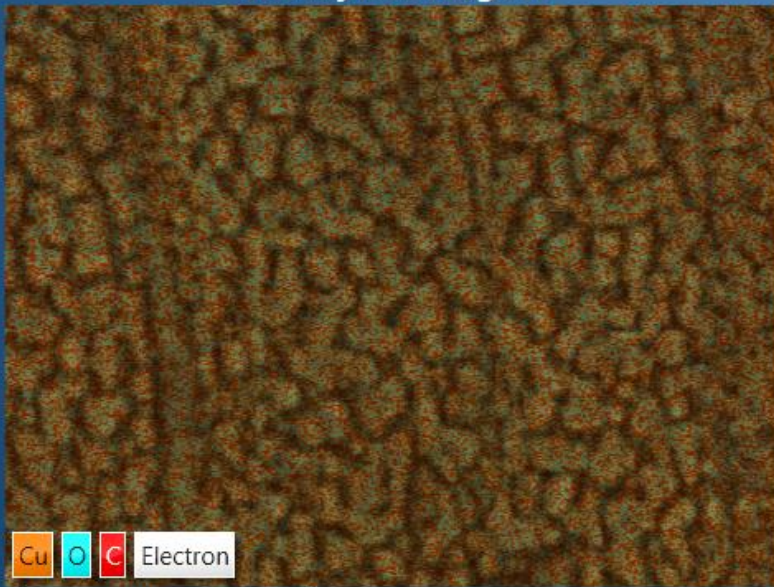
Cryst. Size

Cu(111): 30.18 nm

Cu₂O(111): 10.89 nm



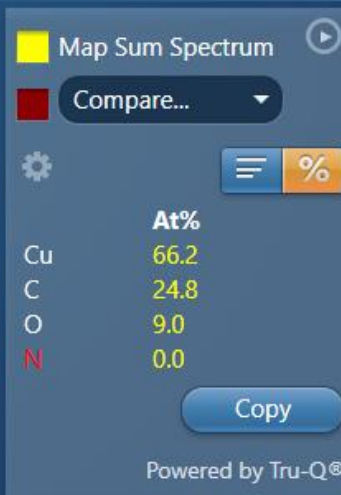
EDS Layered Image 11



500nm



Confirm Elements >>



Cu

Cu

keV

Display



Standard



Settings



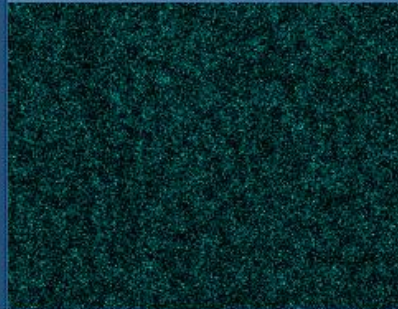
C Kα1_2



500nm



O Kα1



500nm



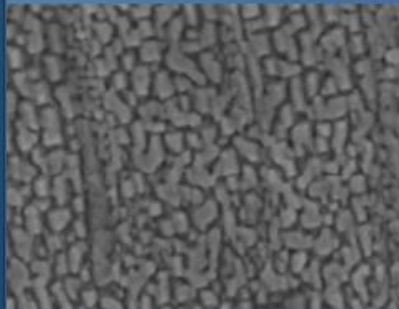
Cu Lα1,2



500nm



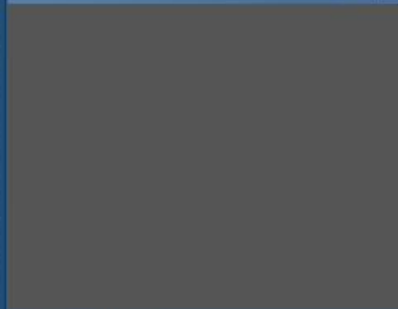
Electron Image 19



500nm



Electron Image 20



500nm

Minimized Maps

Map Display Type: Weight %

Binning Factor: 1

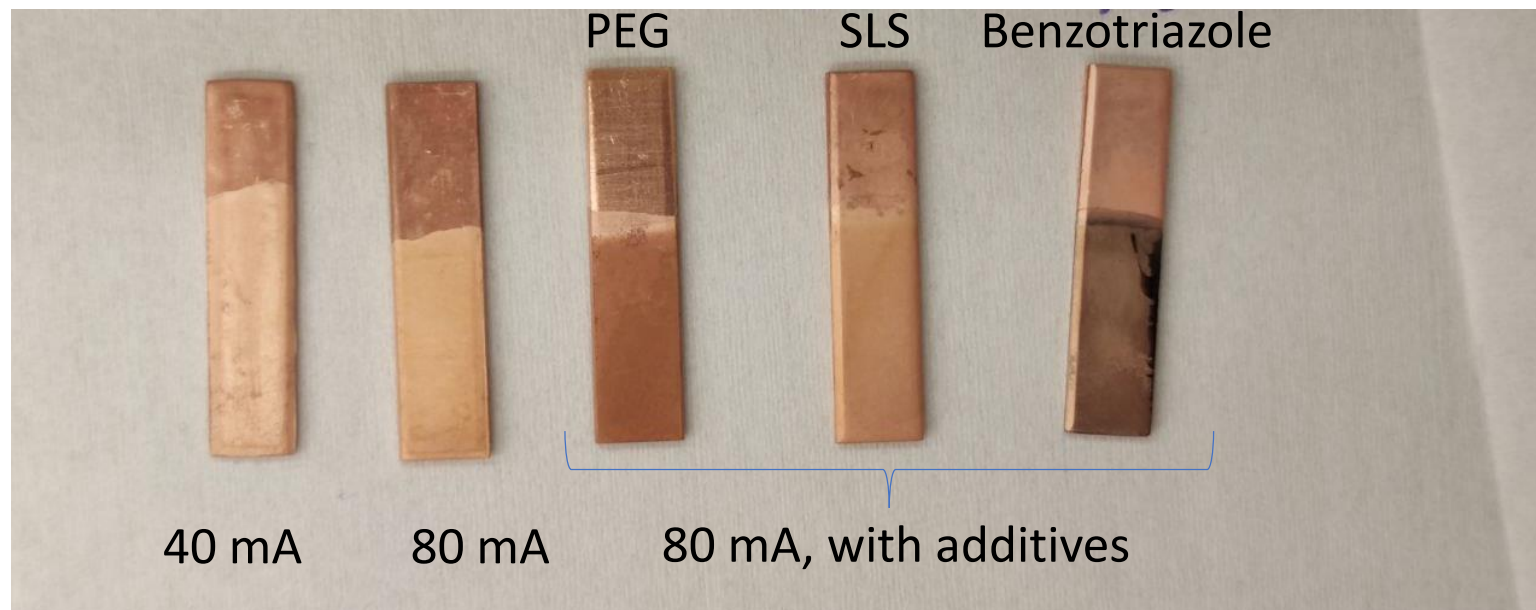


Map Details

11

AutoID

Testing Acidic Electrolytes (1): Cu plating onto Copper



Samples 1-2

$\text{CuSO}_4 \cdot 5\text{H}_2\text{O}$ (0.64M)

H_2SO_4 (0.2 mM)

H_2O

Samples 3-5

$\text{CuSO}_4 \cdot 5\text{H}_2\text{O}$

H_2SO_4

H_2O

and various additives:

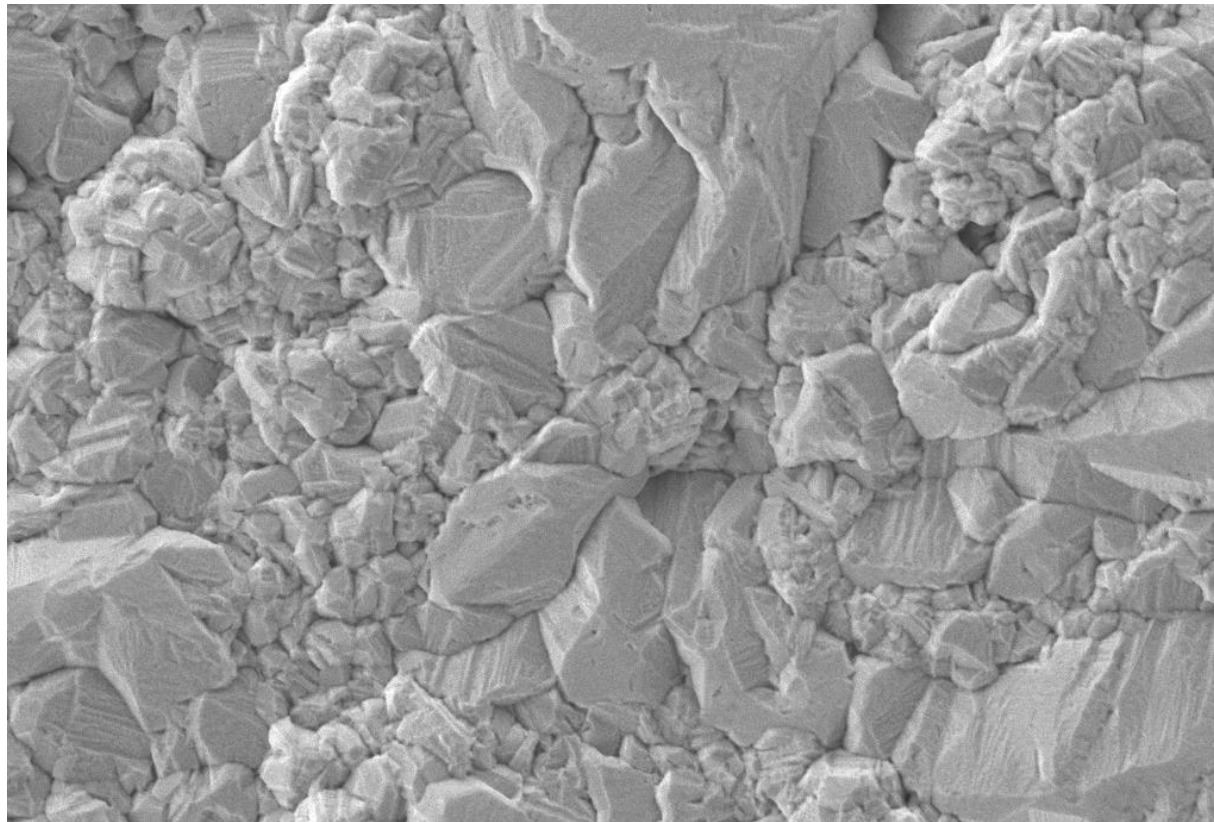
- polyethylene glycol
- sodium lauryl sulphate
- benzotriazole

	I, mA	j, mA/cm ²	deposition rate, um/h	at% O at 5kV	O/Cu at 5kV	Cryst. Size Cu(111), nm
$\text{CuSO}_4 + \text{H}_2\text{SO}_4$	200	27.8	-	3.9	0.05	30.18
$\text{CuSO}_4 + \text{H}_2\text{SO}_4$	40	5.7	7.9	-	-	-
$\text{CuSO}_4 + \text{H}_2\text{SO}_4$	80	13.2	17.4	4.5	0.06	32.76
$\text{CuSO}_4 + \text{H}_2\text{SO}_4 + \text{PEG}$	80	13.2	17.5	5.5-5.9	0.07-0.08	29.86
$\text{CuSO}_4 + \text{H}_2\text{SO}_4 + \text{SLS}$	80	13.2	17.4	3.6	0.05	32.84
$\text{CuSO}_4 + \text{H}_2\text{SO}_4$ + benzotriazole	80	14	19.2	2-4.3	0.03-0.06	23.9

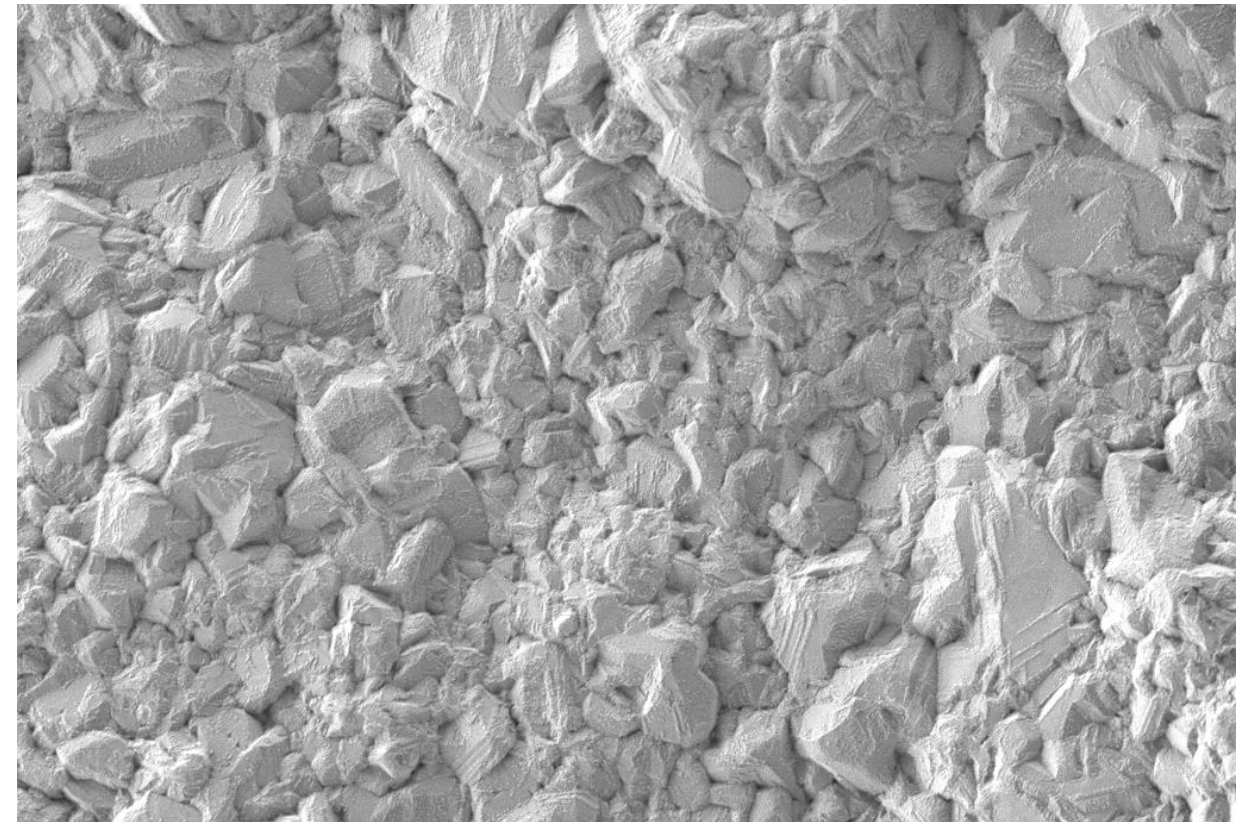
Cu-film morphology: General view (SEM)

Current density effect

40 mA



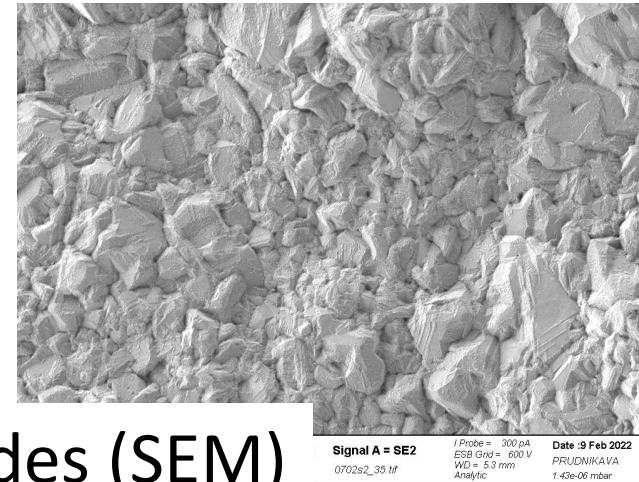
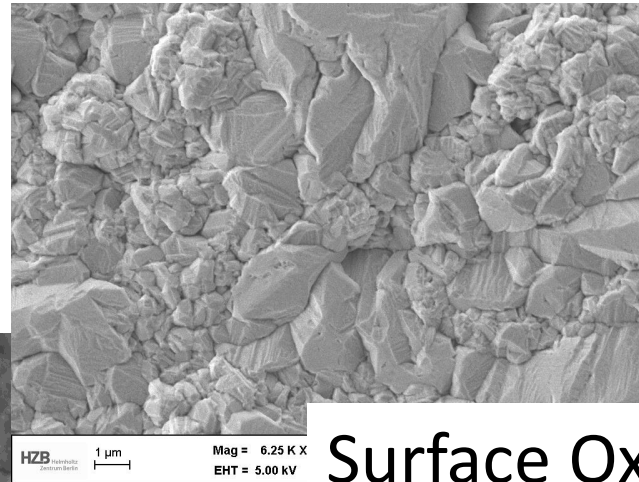
80 mA



Testing Acidic Electrolytes (1): Cu plating onto Copper

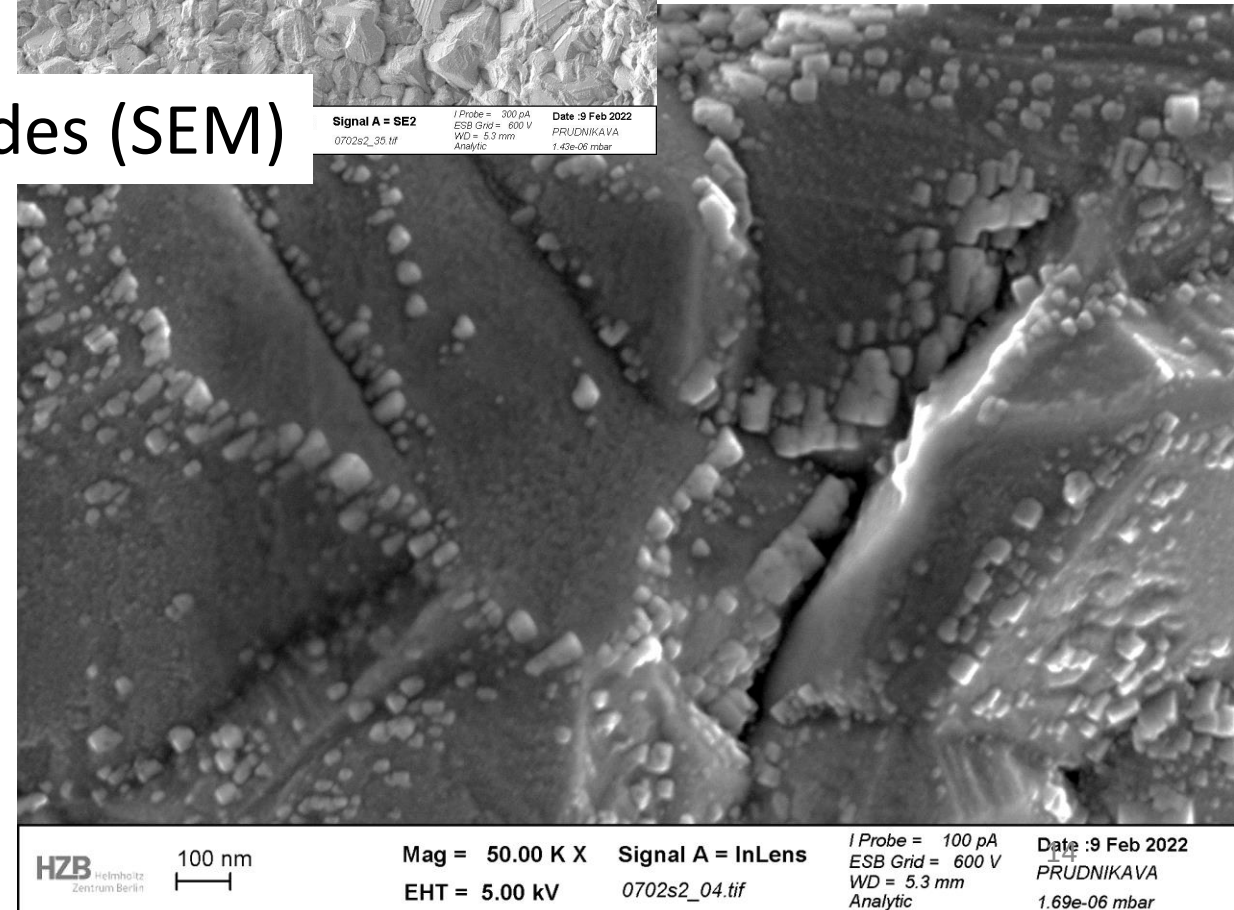
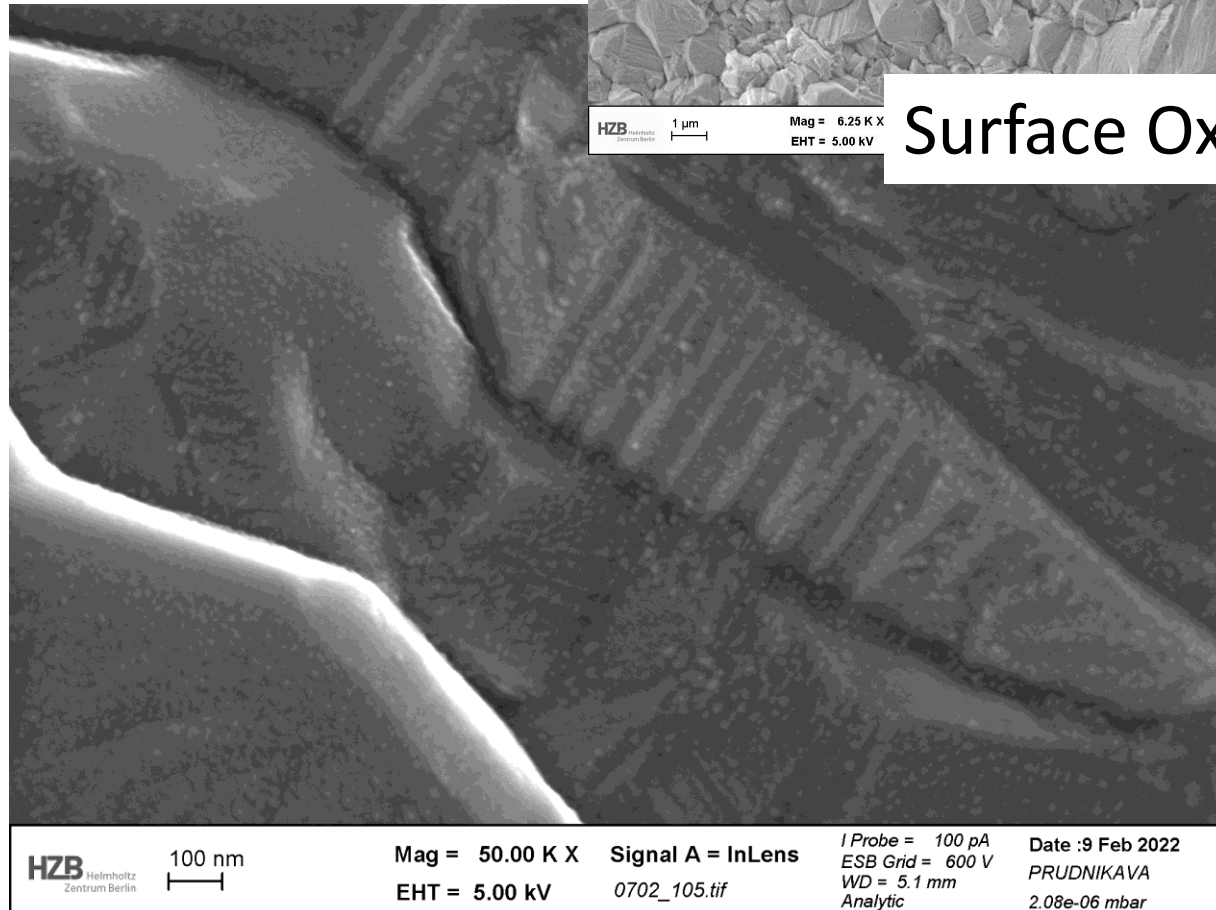
Higher current => larger
 Cu_2O precipitates

40 mA



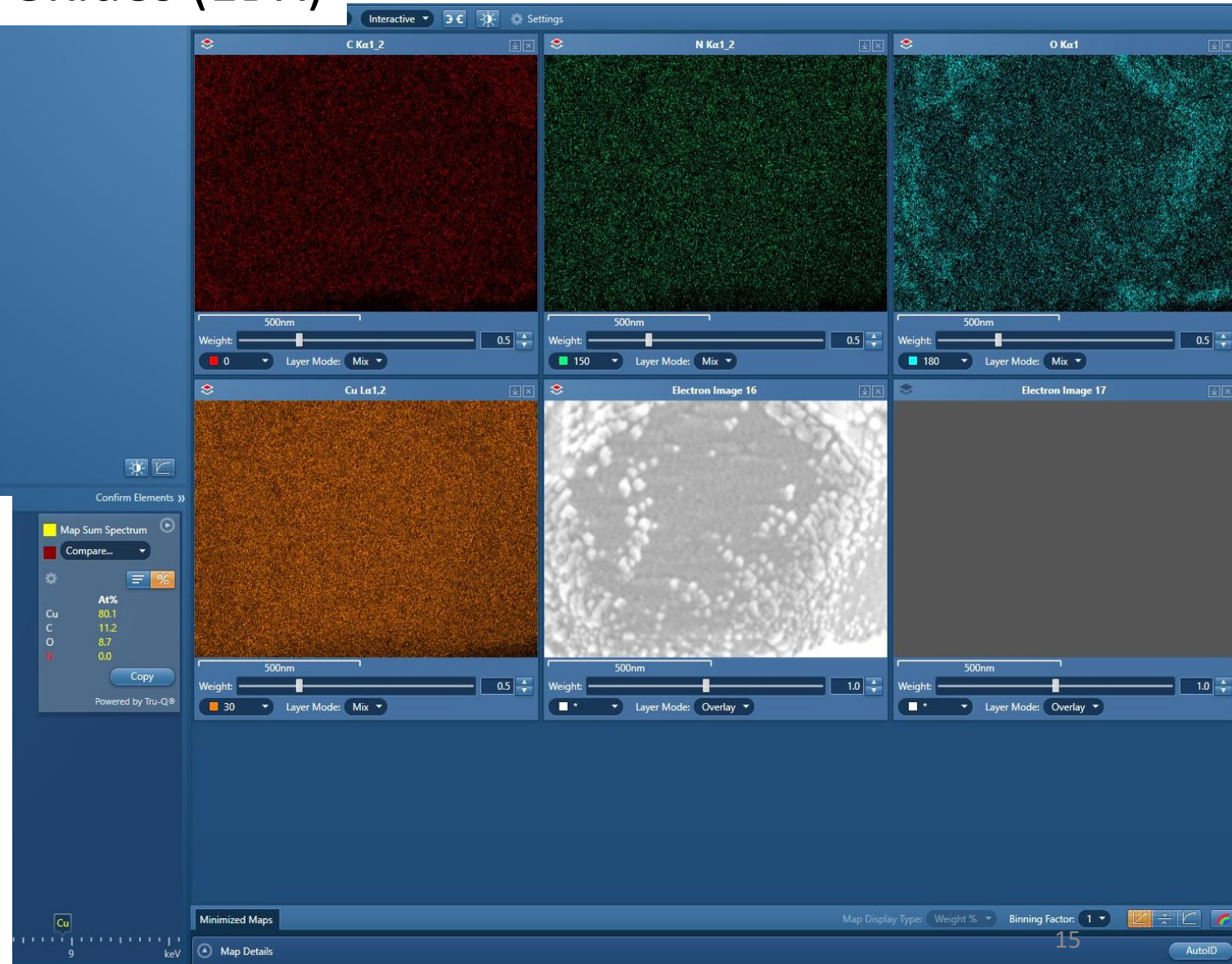
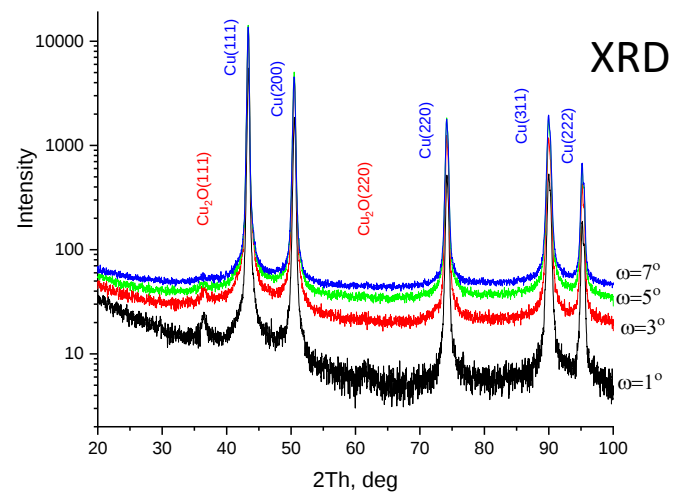
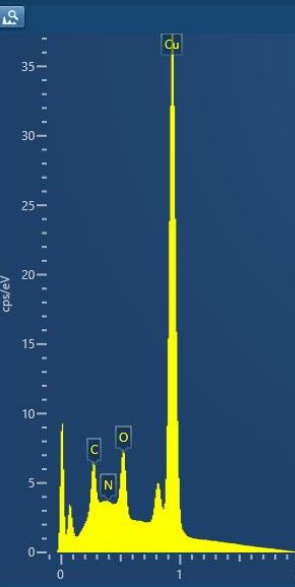
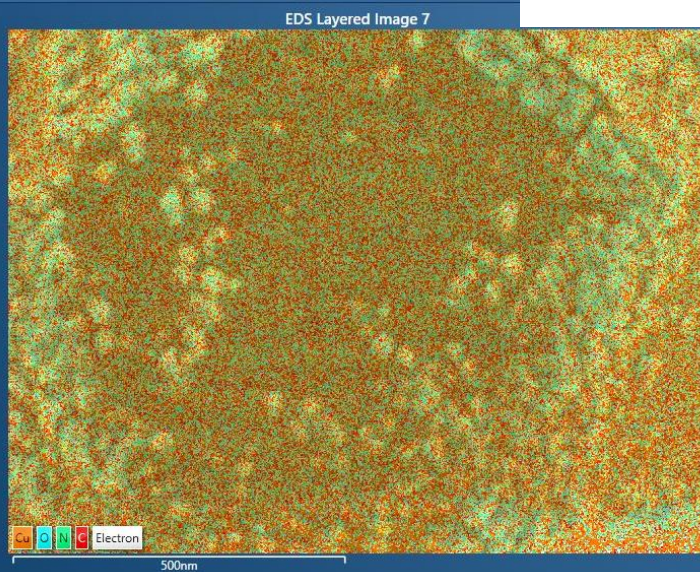
80 mA

Surface Oxides (SEM)



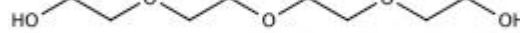
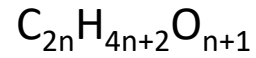
80 mA

EDX

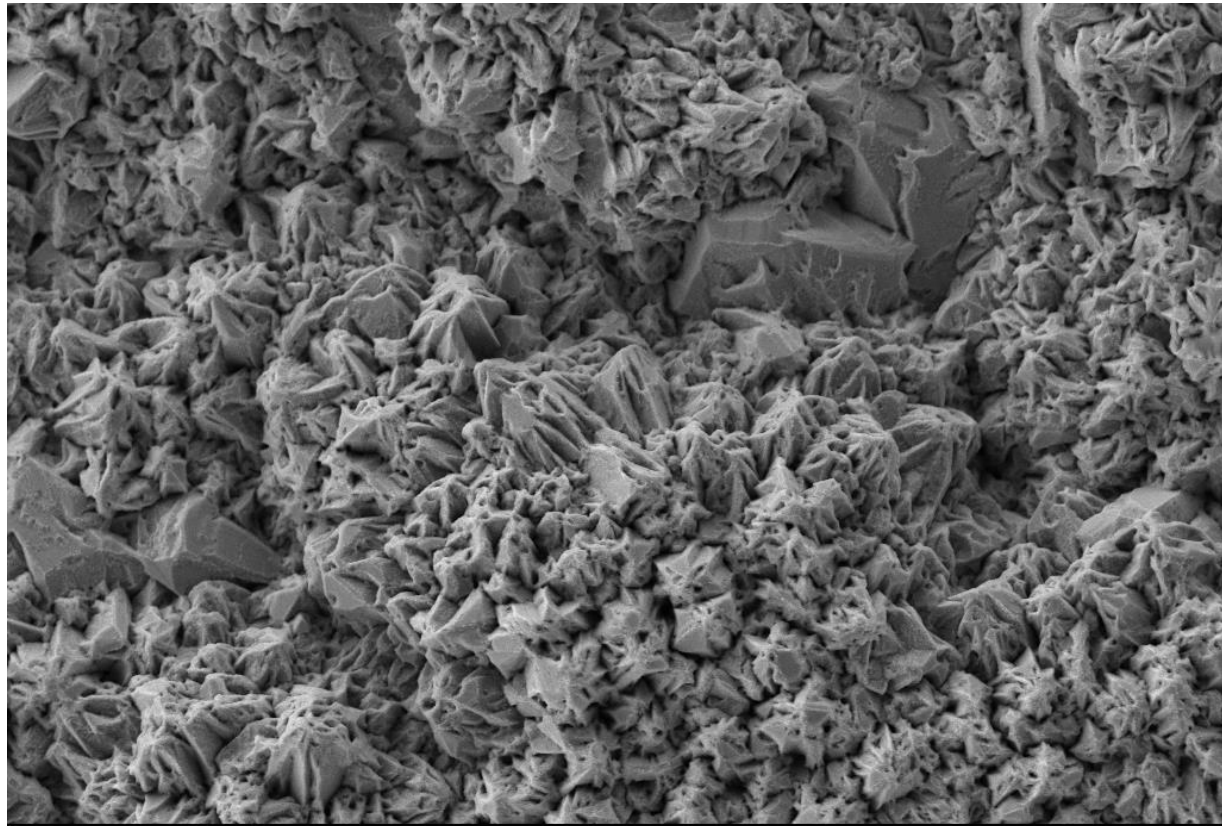
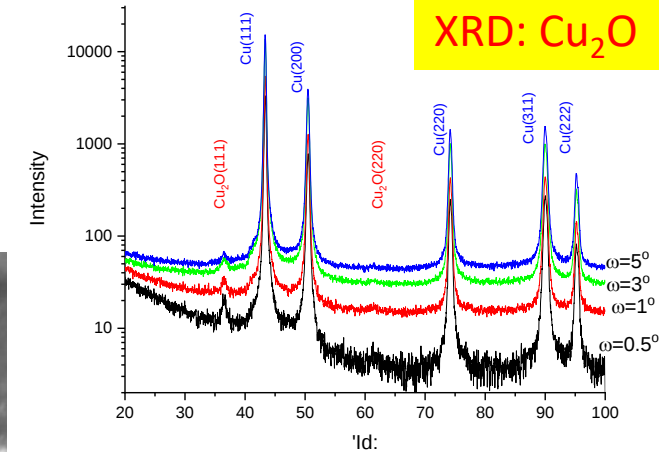


Testing Acidic Electrolytes (1): Cu plating onto Copper

with Polyethylene glycol



XRD: Cu₂O



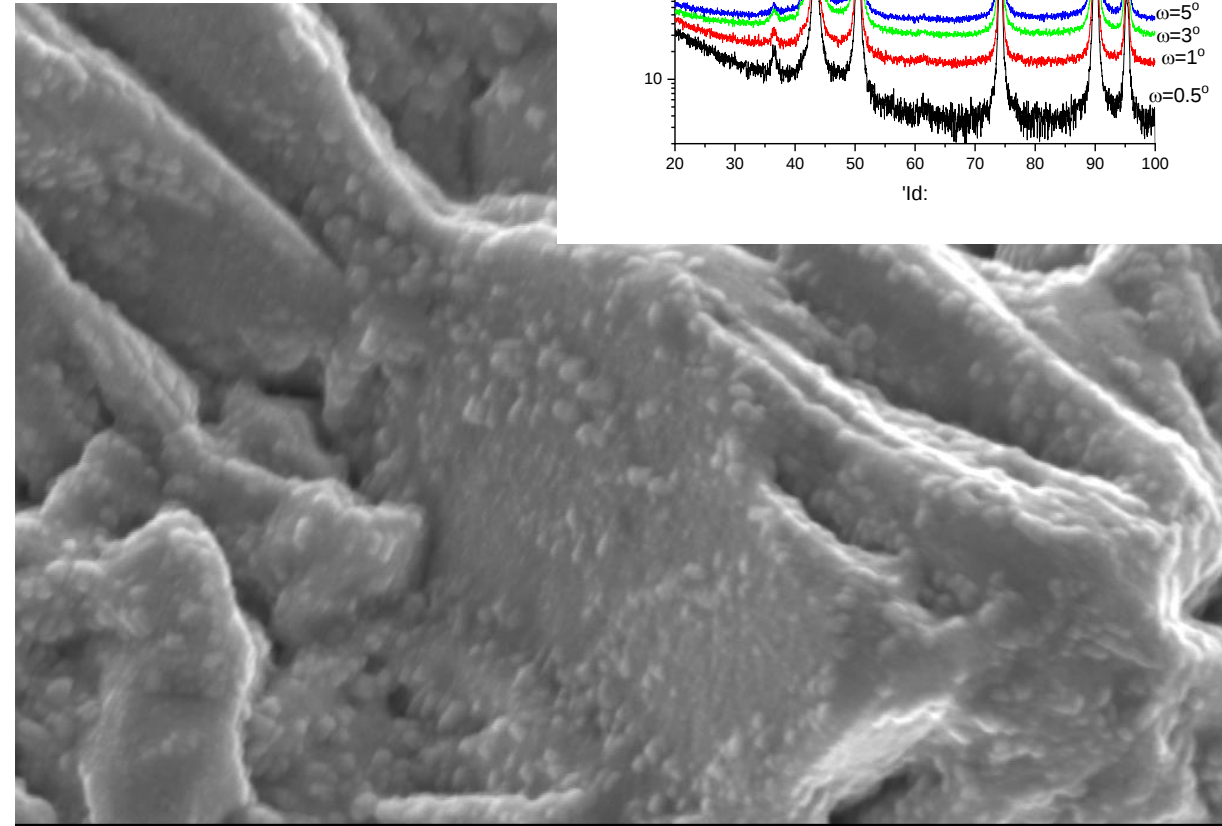
HZB Helmholtz
Zentrum Berlin

1 μm

Mag = 5.00 K X **Signal A = SE2**
EHT = 5.00 kV 0702s3_06.tif

*I Probe = 300 pA
ESB Grid = 600 V
WD = 5.2 mm
Analytic*

Date :10 Feb 2022
PRUDNIKAVA
2.06e-06 mbar



HZB Helmholtz
Zentrum Berlin

200 nm

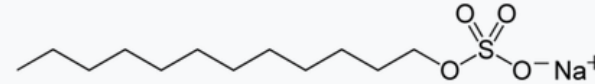
Mag = 50.00 K X **Signal A = InLens**
EHT = 5.00 kV 0702s3_04.tif

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ESB Grid = 600 V
WD = 5.2 mm
Analytic*

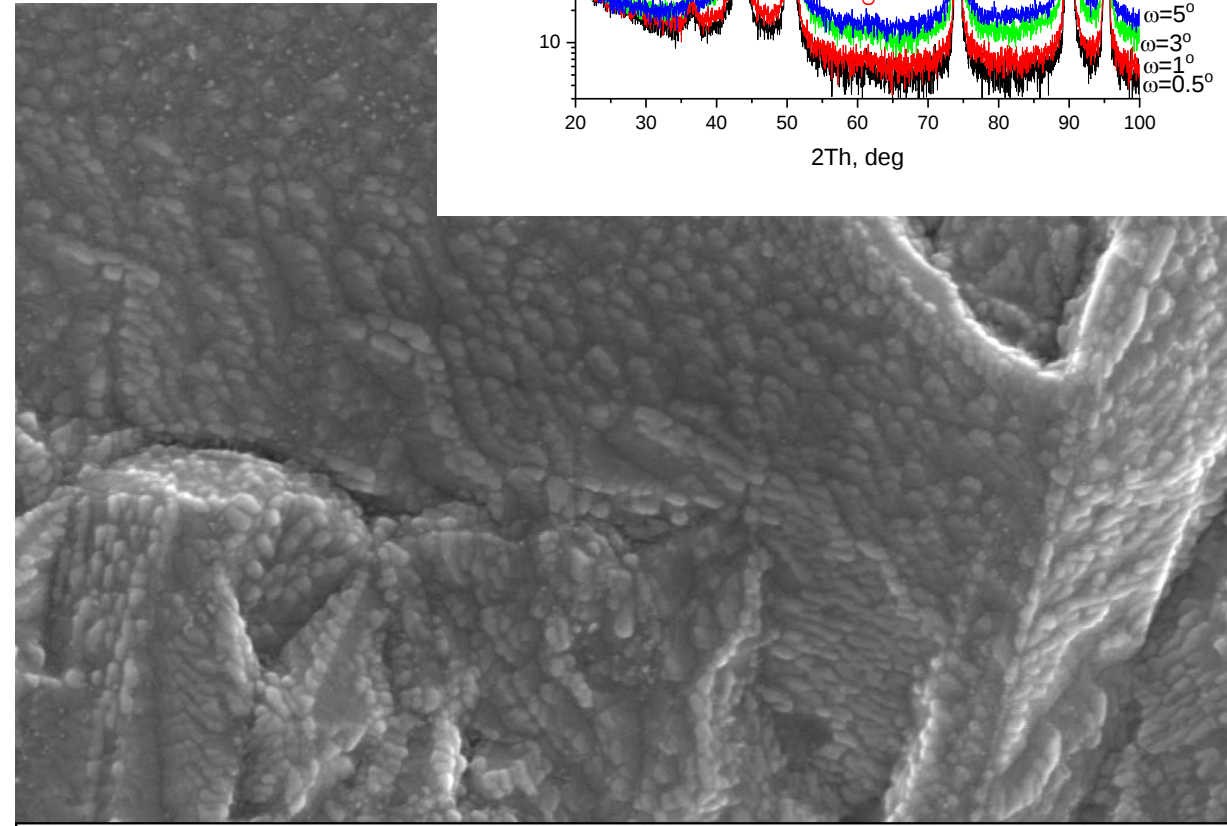
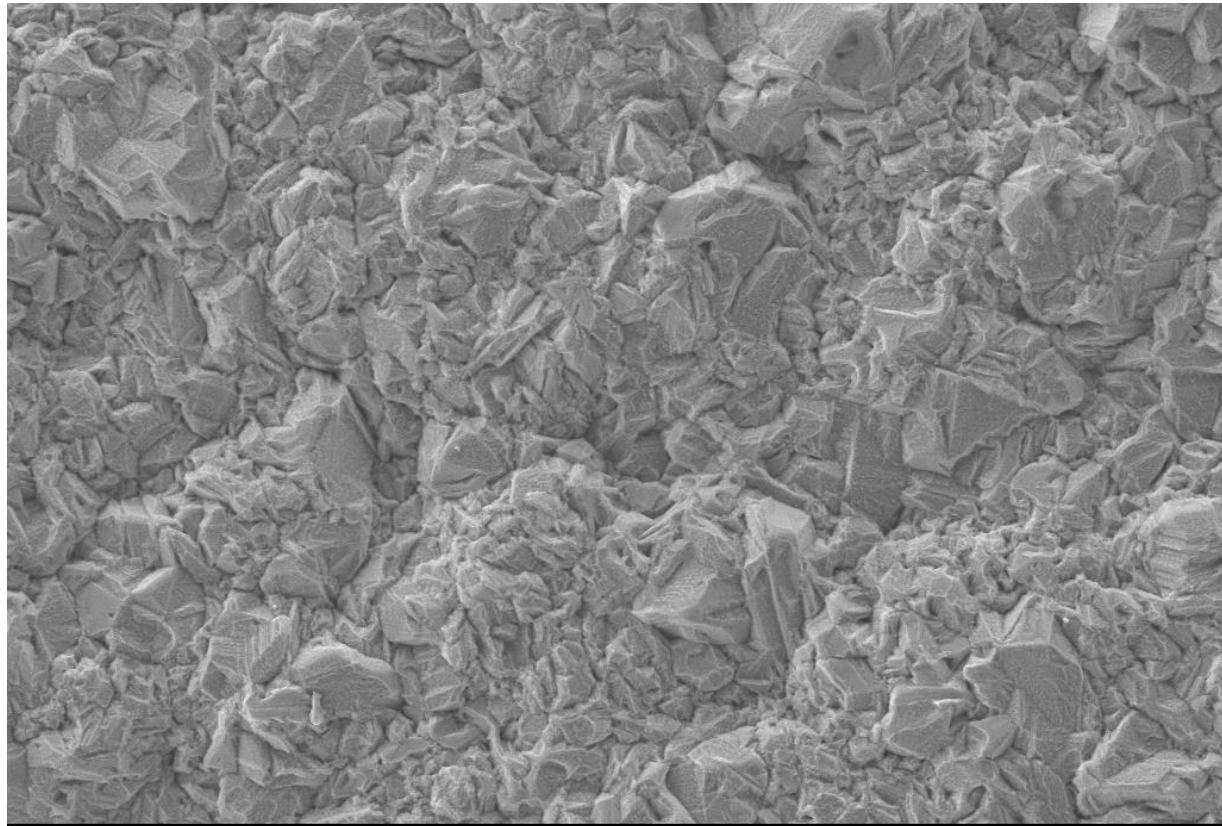
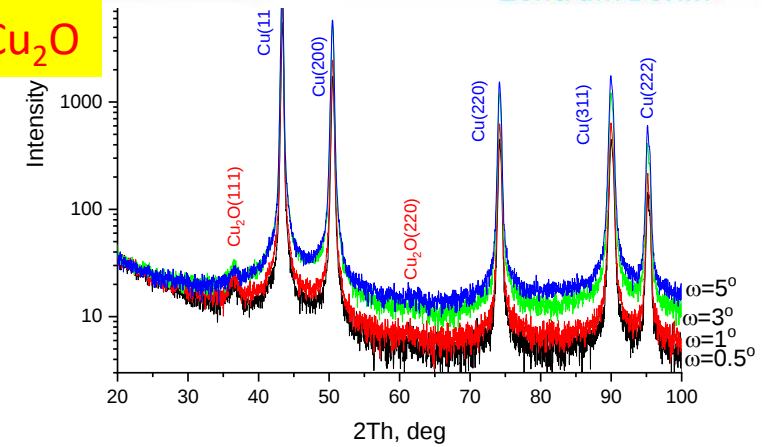
Date :10 Feb 2022
PRUDNIKAVA
2.13e-06 mbar

Testing Acidic Electrolytes (1): Cu plating onto Copper

with Sodium Lauryl Sulphate

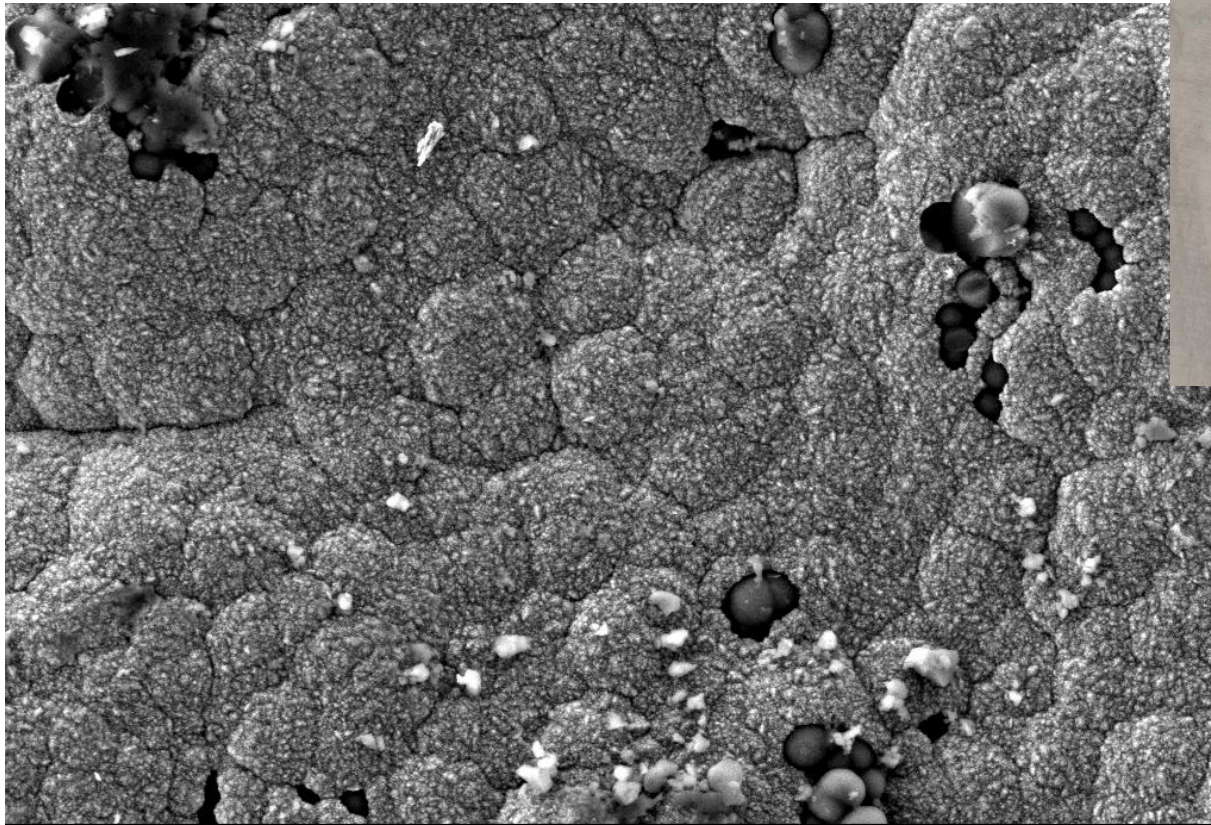
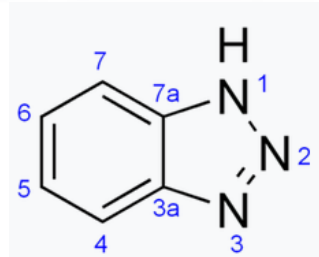


XRD: Cu₂O



Testing Acidic Electrolytes (1): Cu plating onto Copper

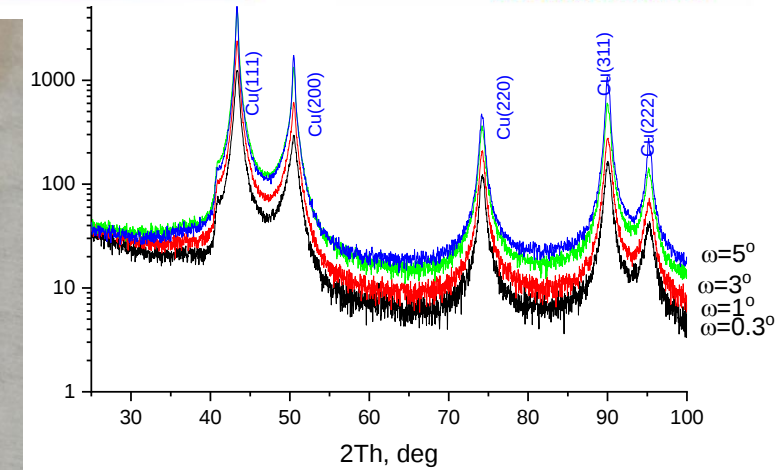
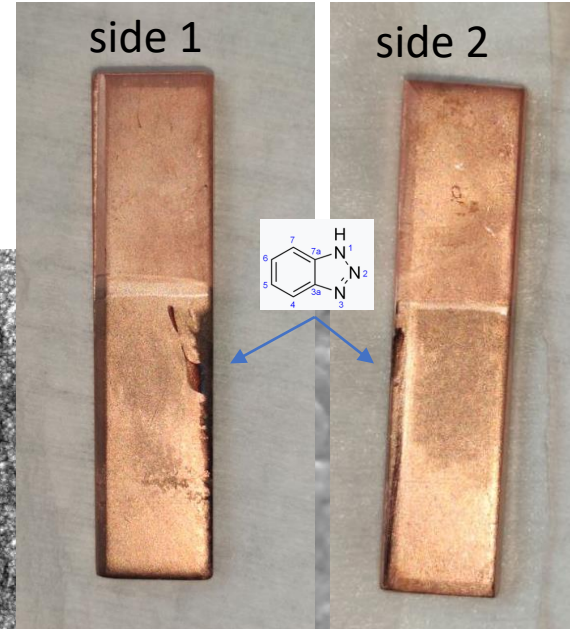
with benzotriazole



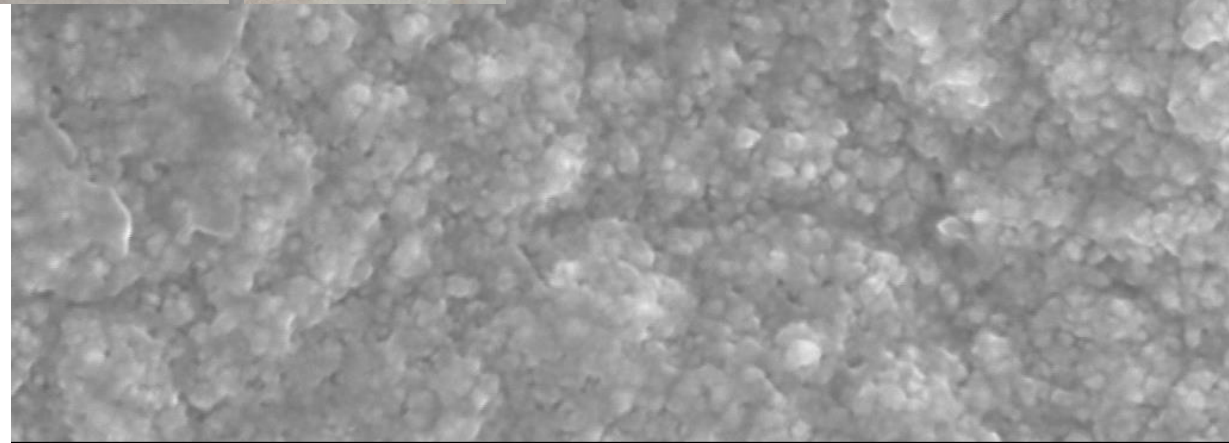
HZB Helmholtz
Zentrum Berlin

1 μ m

Mag = 5.00 K X Signal A = SE2 I Probe = 300 pA Date : 14 Feb 2022
EHT = 5.00 kV 0702s5_07.tif ESB Grid = 600 V PRUDNIKAVA
Analytic 1.88e-06 mbar



XRD: no Cu_2O
 $\text{C}_6\text{H}_5\text{N}_3$ residue



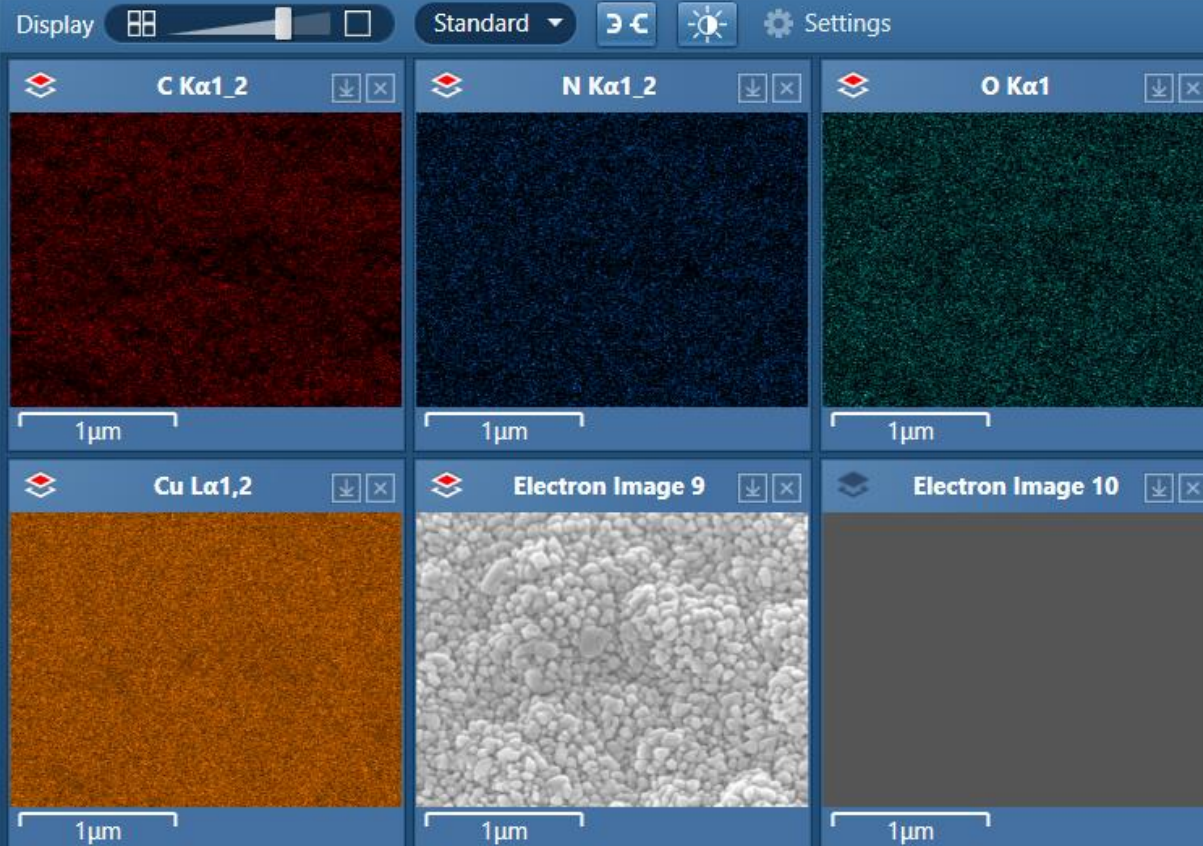
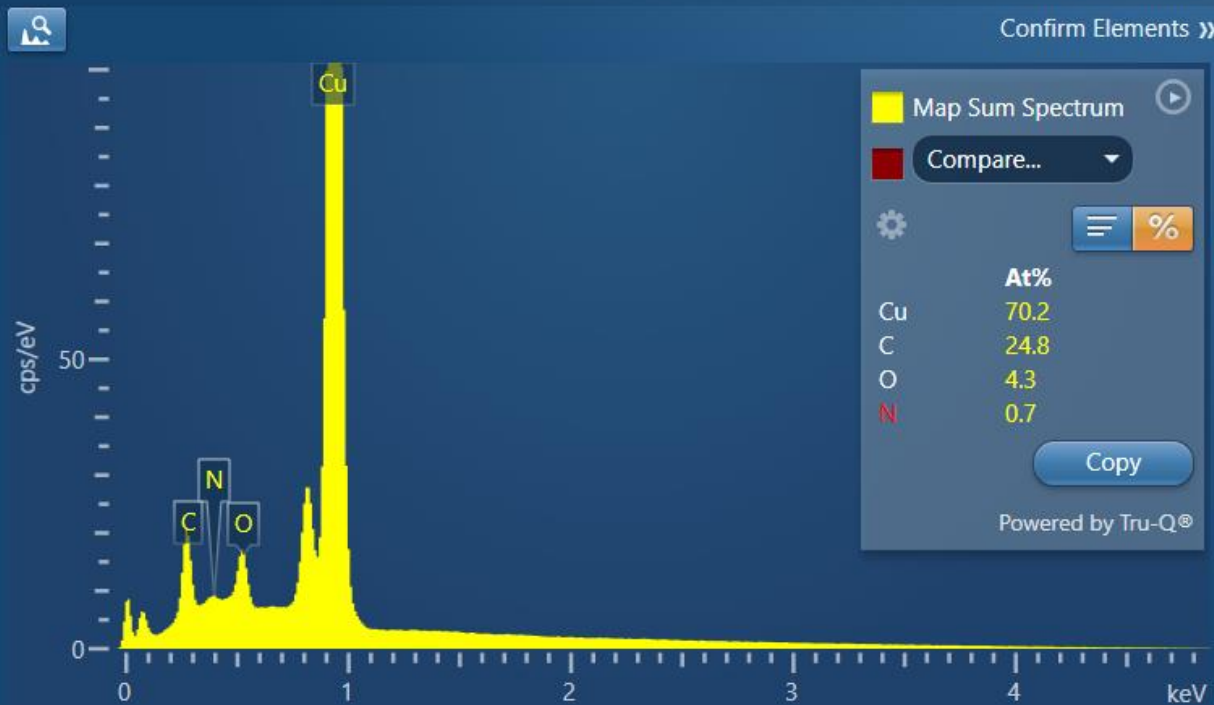
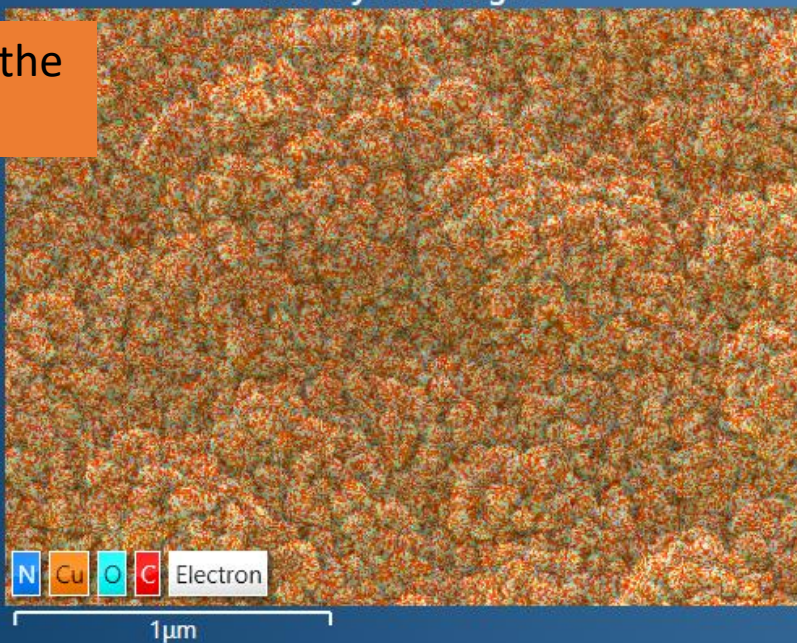
HZB Helmholtz
Zentrum Berlin

100 nm

Mag = 70.00 K X Signal A = InLens I Probe = 300 pA Date : 14 Feb 2022
EHT = 5.00 kV 0702s5_27.tif ESB Grid = 600 V PRUDNIKAVA
Analytic 1.60e-06 mbar

EDS Layered Image 6

Top area of the electrode



Minimized Maps

Map Display Type: Weight %

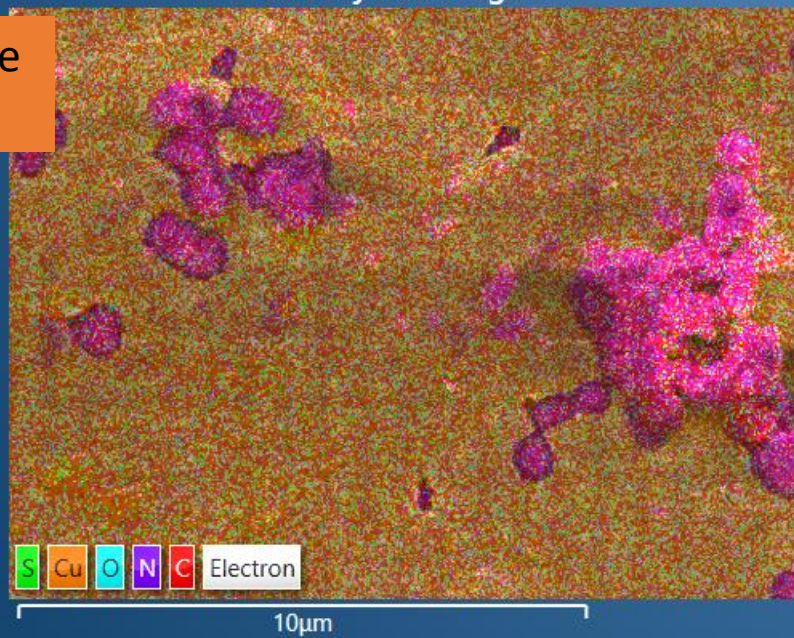
Binning Factor: 1

Map Details

AutoID

EDS Layered Image 7

Middle of the electrode



Display



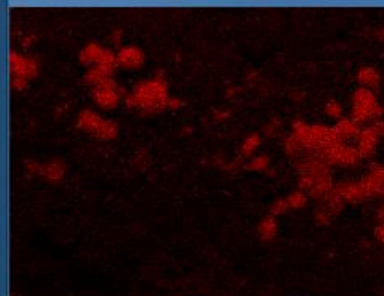
Standard



Settings



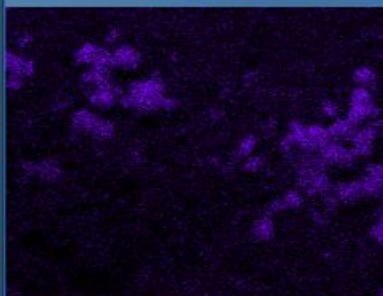
C Kα1_2



10µm



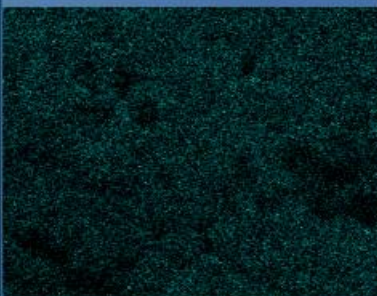
N Kα1_2



10µm



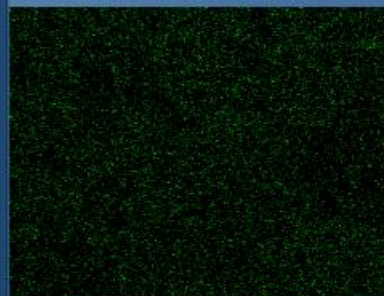
O Kα1



10µm



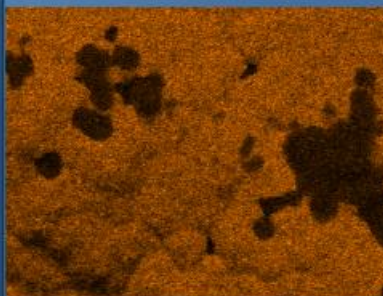
S Kα1



10µm



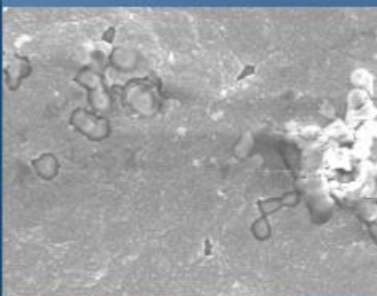
Cu Lα1,2



10µm



Electron Image 11



10µm



Electron Image 12



10µm

Minimized Maps

Map Display Type:

Weight %

Binning Factor:

1



Map Details

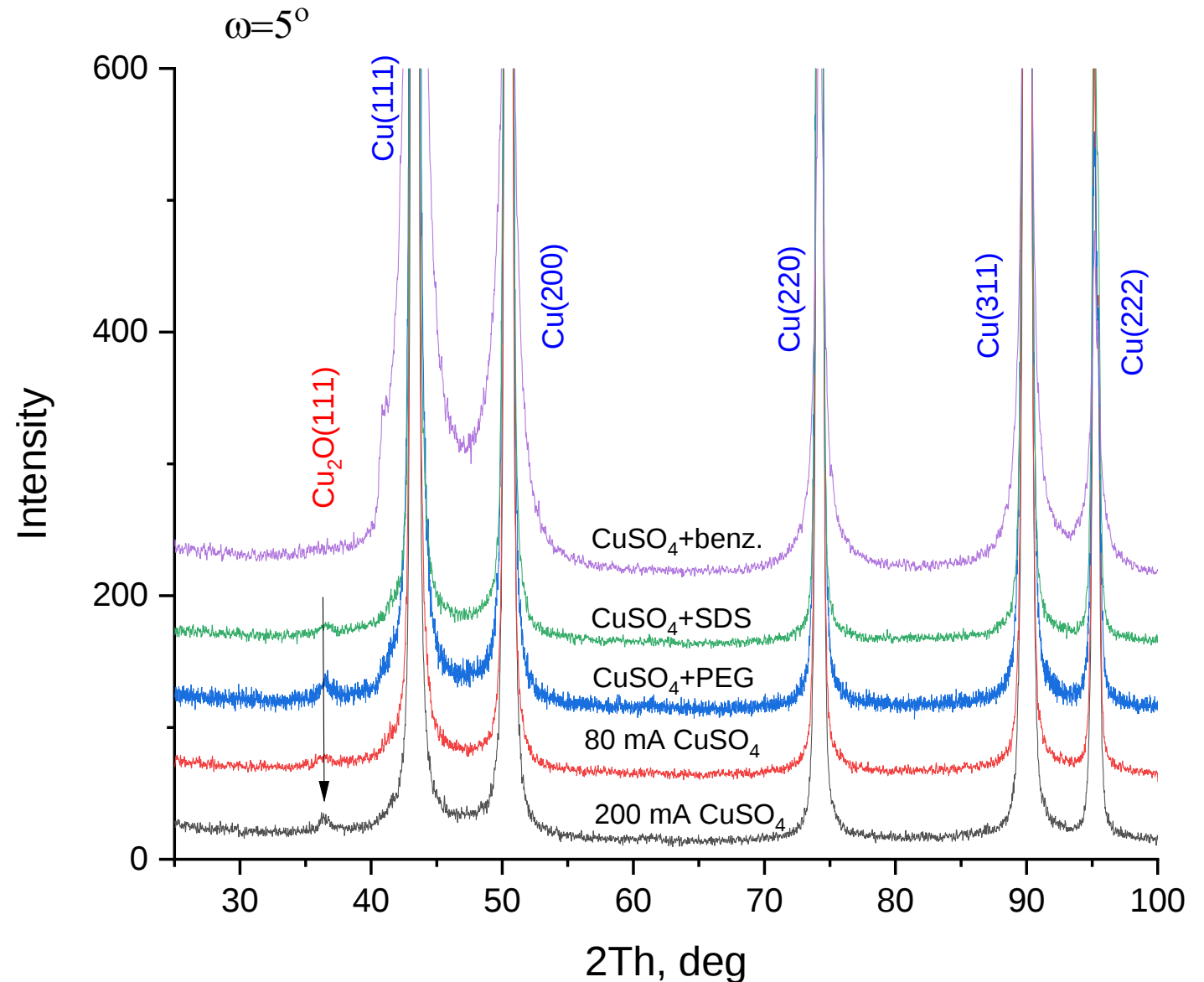
20

AutoID

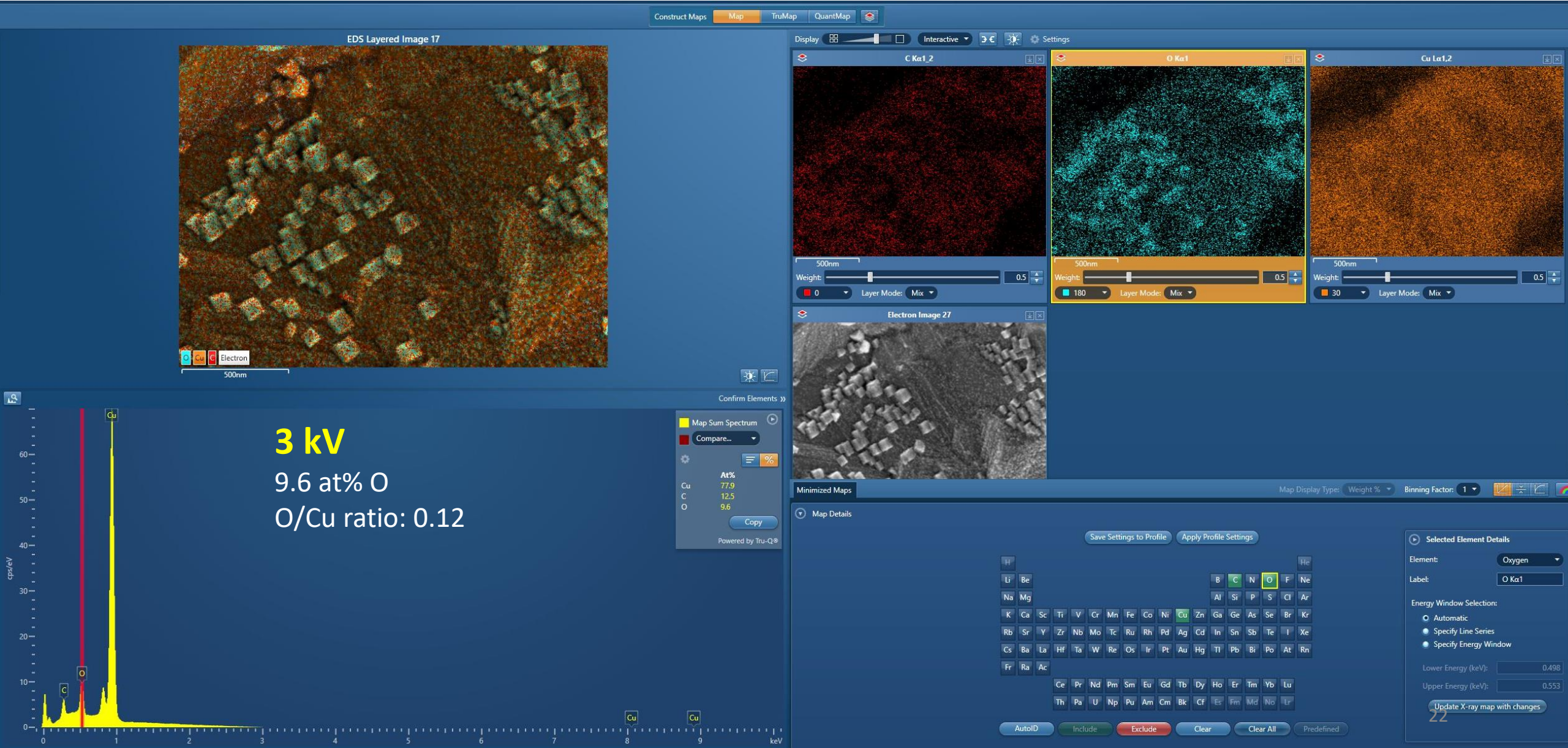
XRD

comparison at $\omega=5^\circ$

only benzotriazole additive
affects the Cu_2O formation



Cu electrode surface after chemical etching



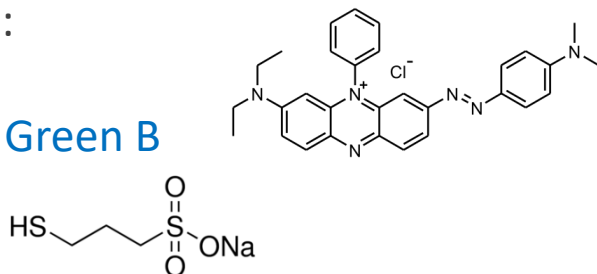
Testing Acidic Electrolytes (2): Cu plating onto Copper

Electrolyte:



additives:

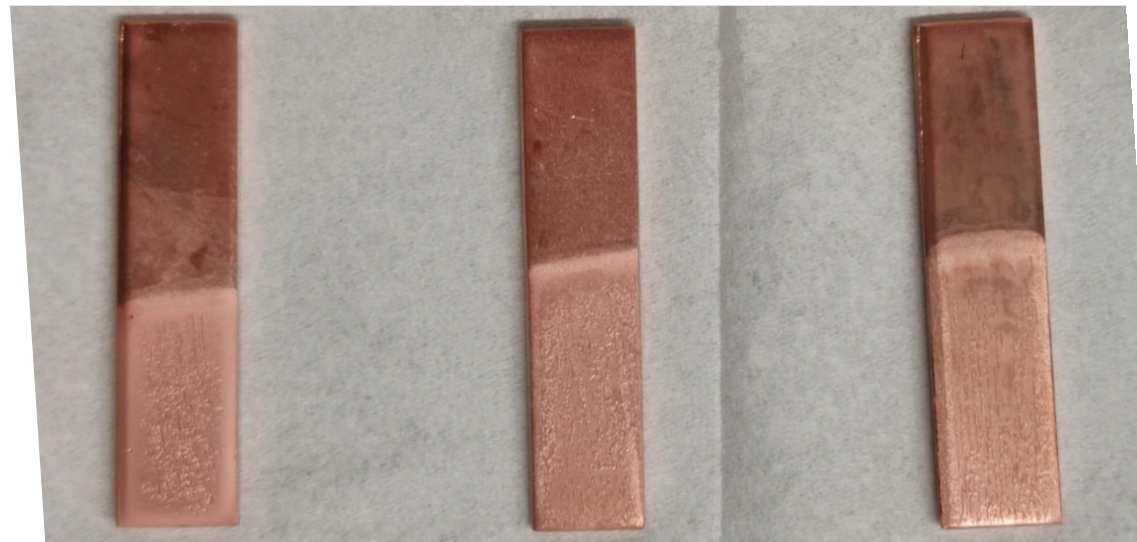
- NaCl
- Janus Green B
- MPS



Sample 1

Sample 2

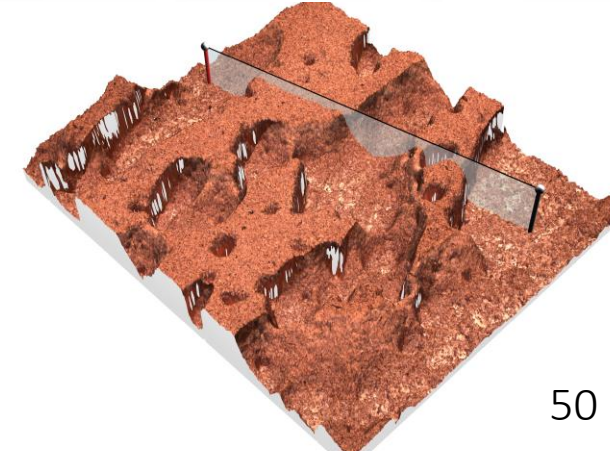
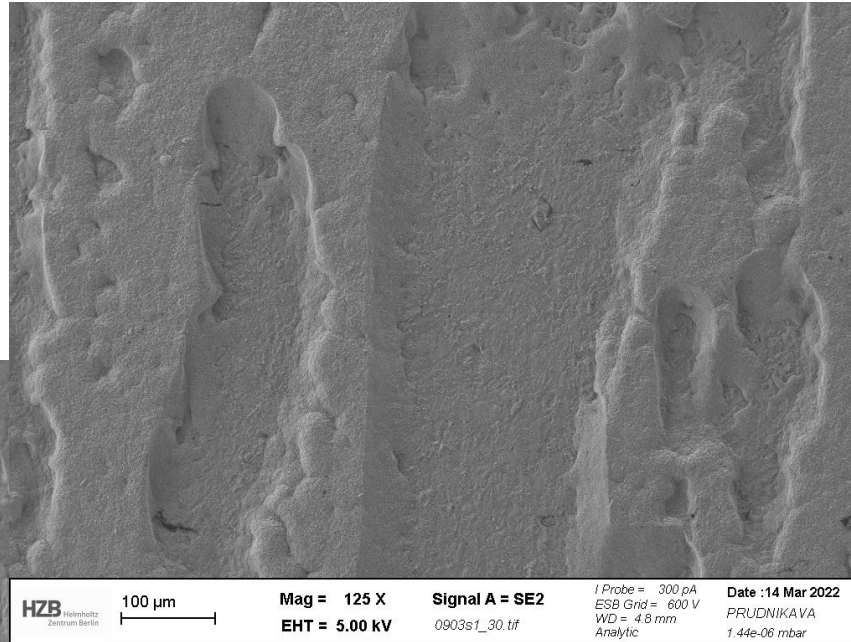
Sample 3



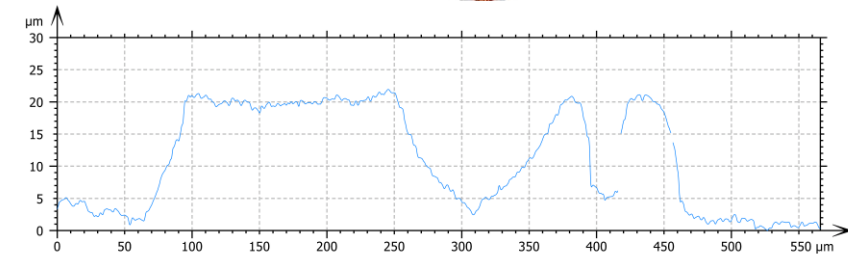
	I, mA	j, mA/cm ²	deposition rate, um/h	at% O at 5kV	O/Cu at 5kV	Cryst. Size Cu(111), nm
$\text{CuSO}_4 + \text{H}_2\text{SO}_4 + \text{NaCl}$ +Janus Green B	80	17.6	24.5	2.1-3.6	0.02-0.04	29.64
$\text{CuSO}_4 + \text{H}_2\text{SO}_4 + \text{NaCl}$ +Janus Green B	50	13.2	13.5	2.7	0.03	33.28
$\text{CuSO}_4 + \text{H}_2\text{SO}_4 + \text{NaCl}$ +Janus Green B+MPS	50	13.2	12.9	3.5-4	0.04-0.05	33.40

Testing Acidic Electrolytes (2): Cu plating onto Copper

80 mA

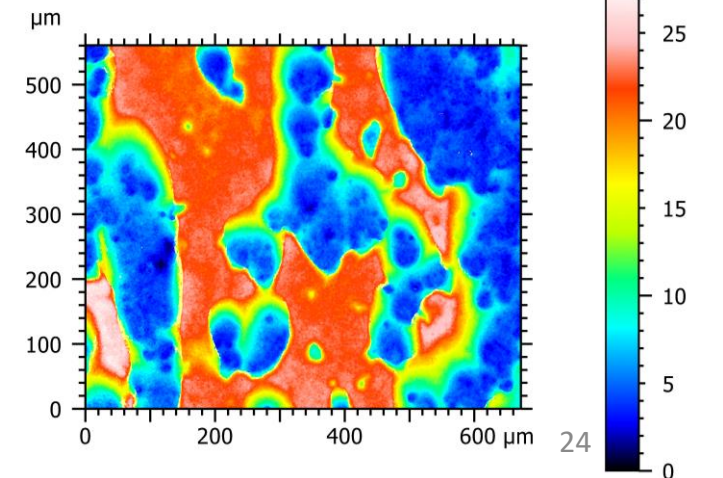
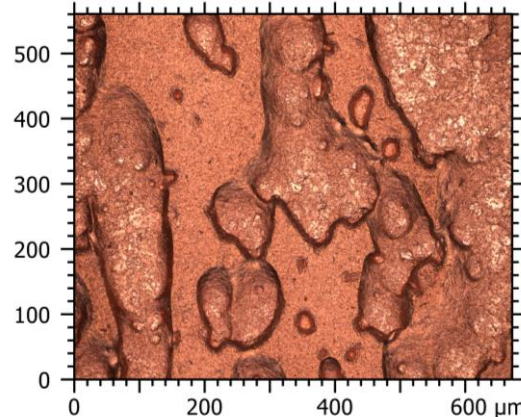


50 mA



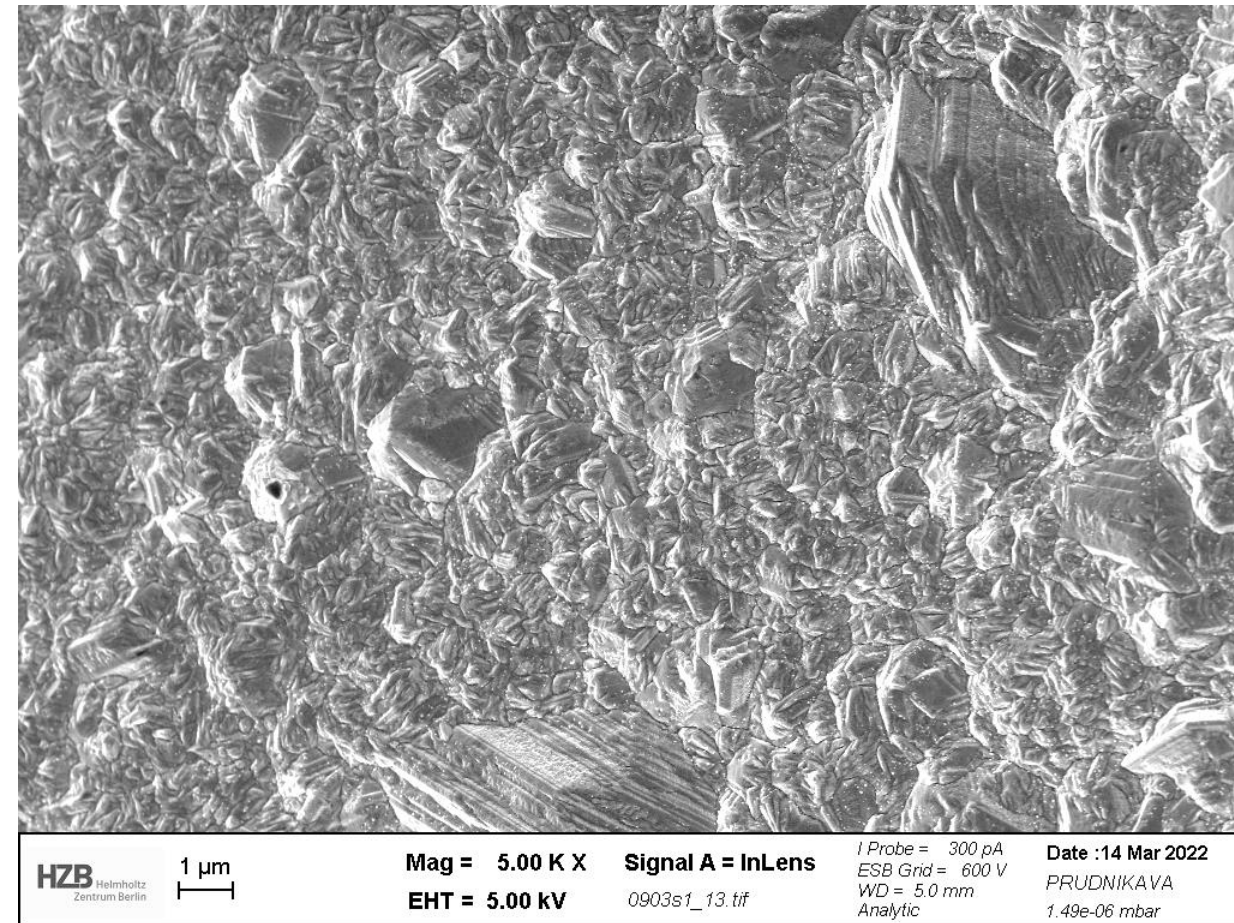
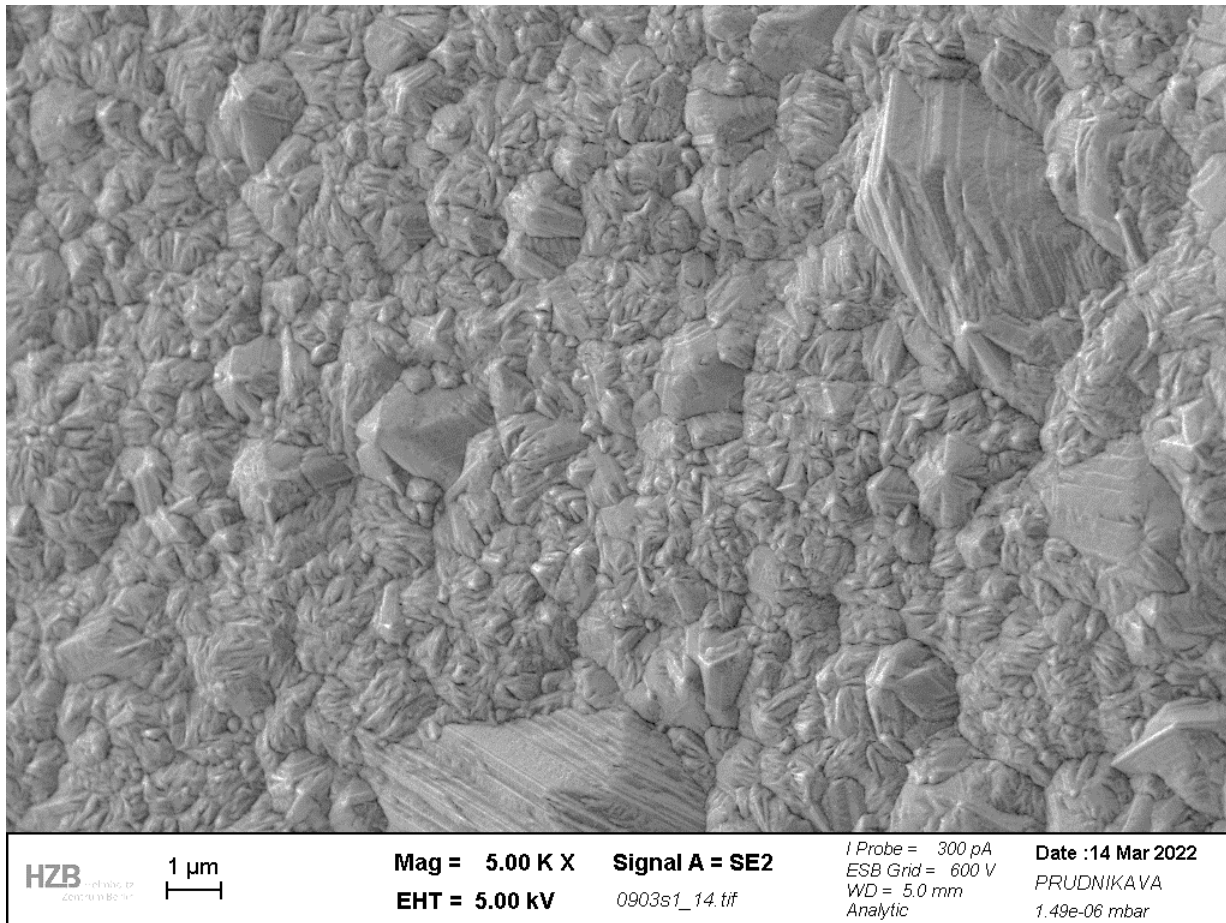
Parameters	Value	Unit
Length	566.0	μm

x 20

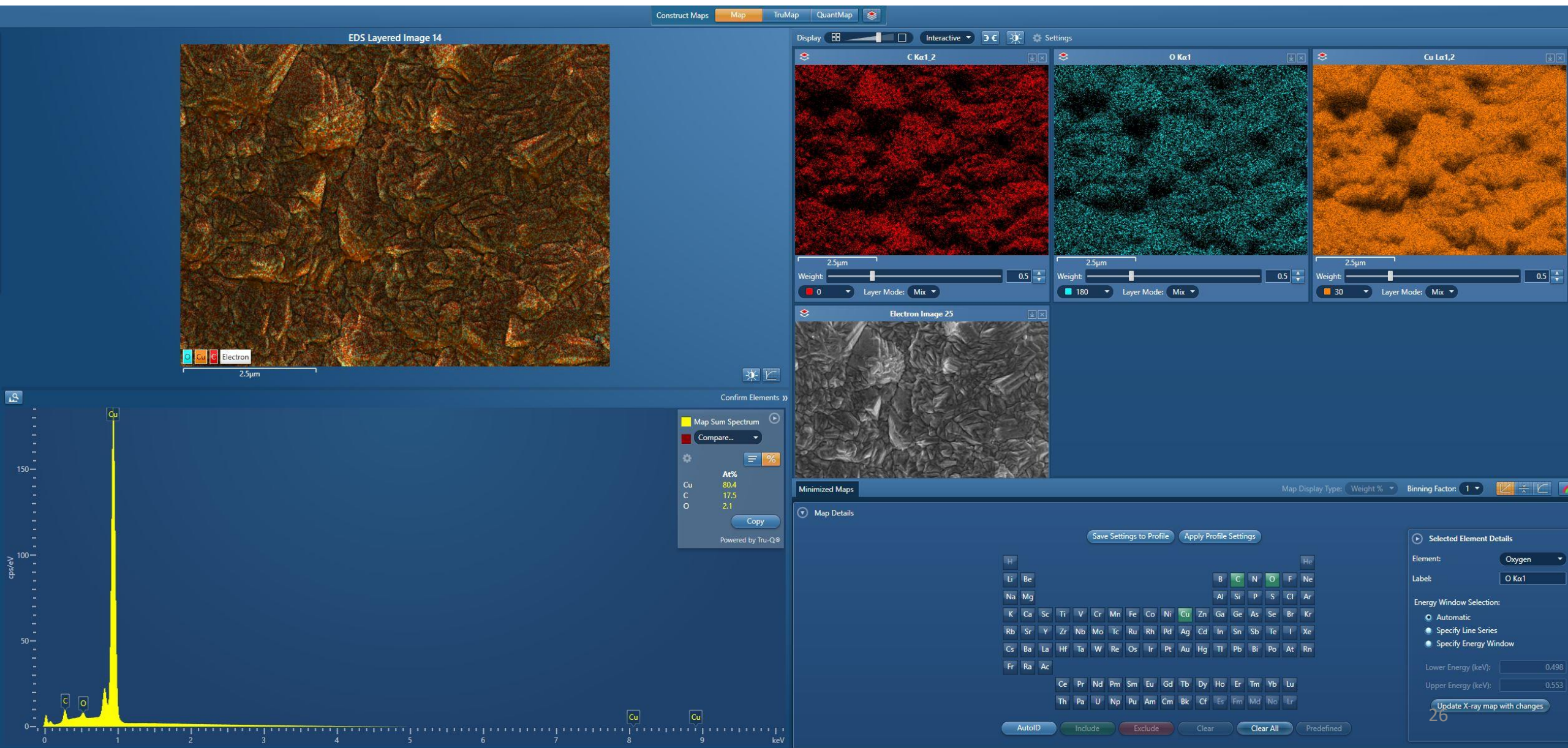


Morphology of the Cu-films (SEM)

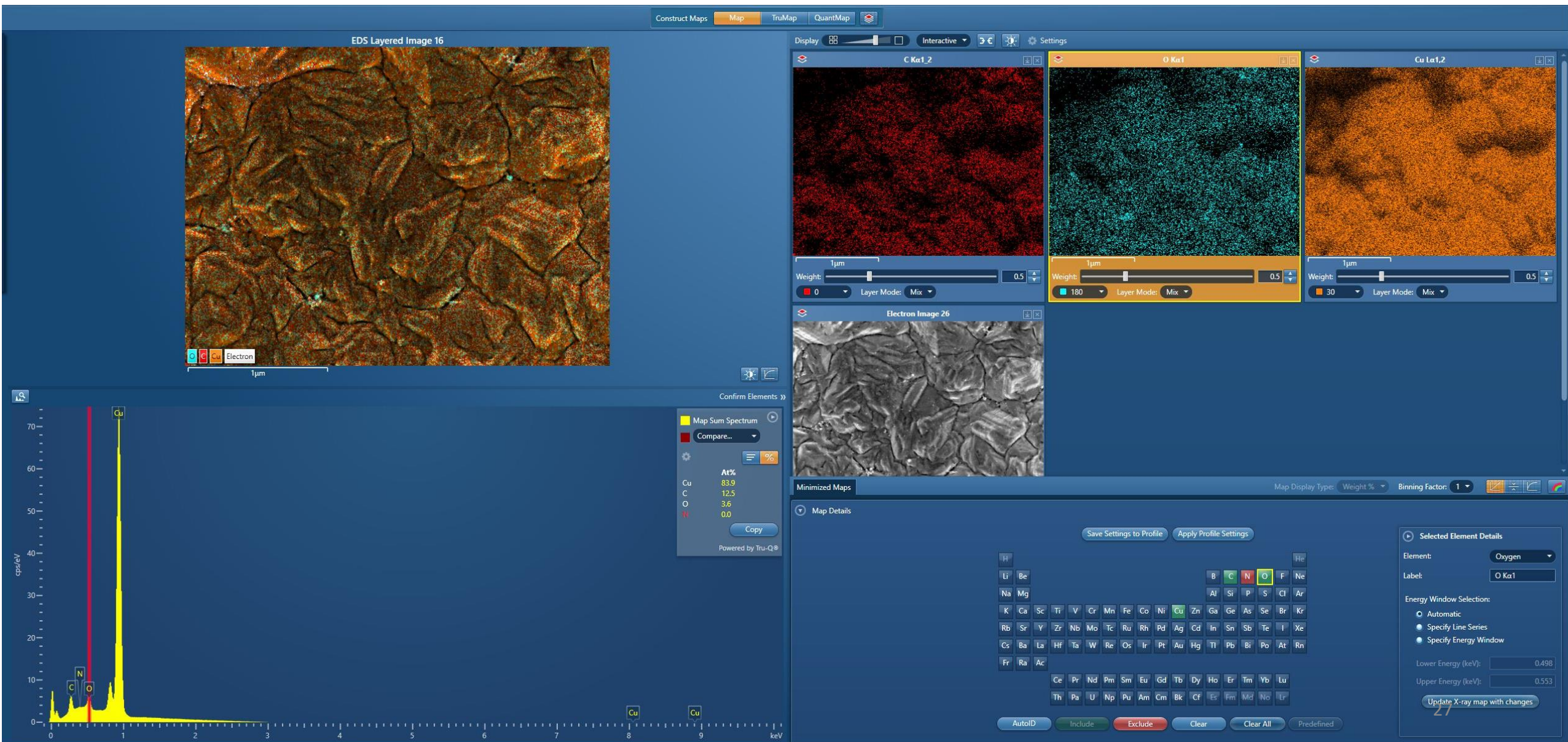
80 mA



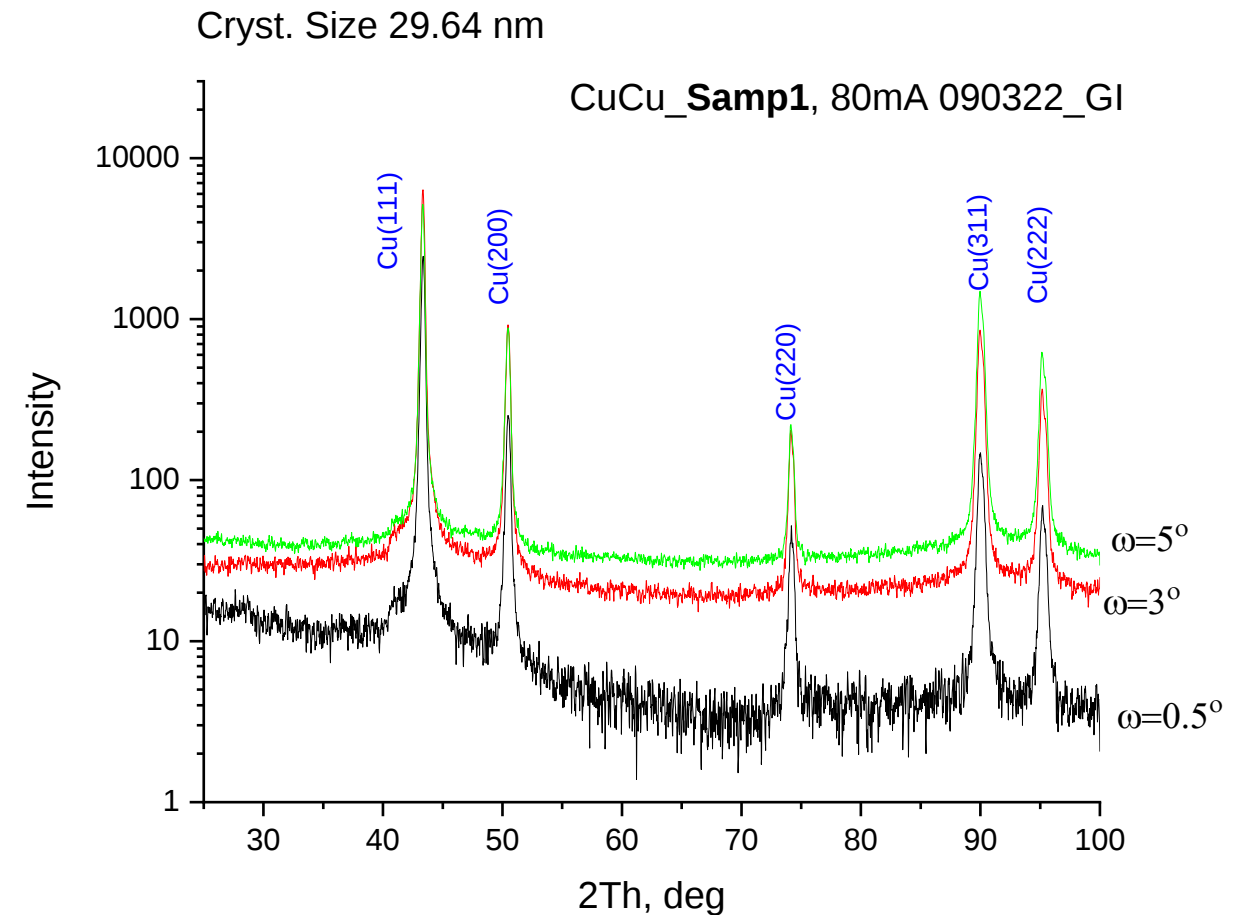
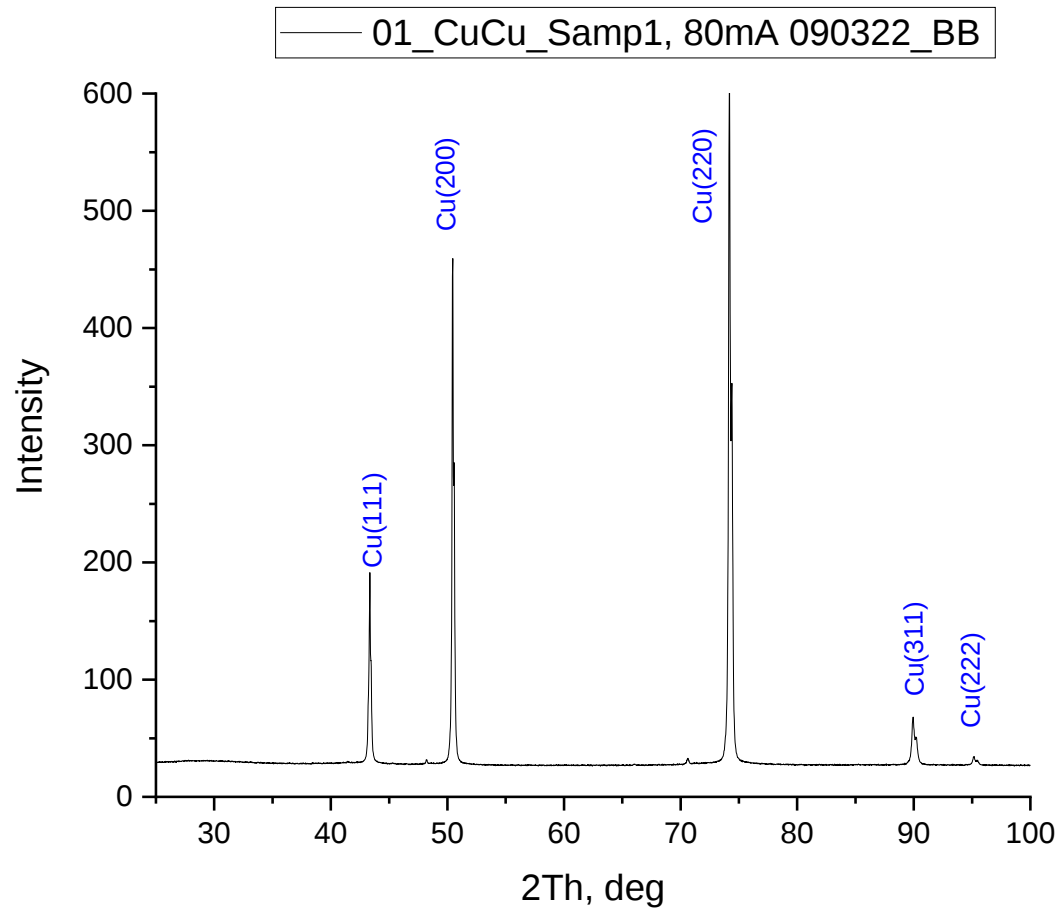
Sample 1, 80 mA



Sample 1, 80 mA

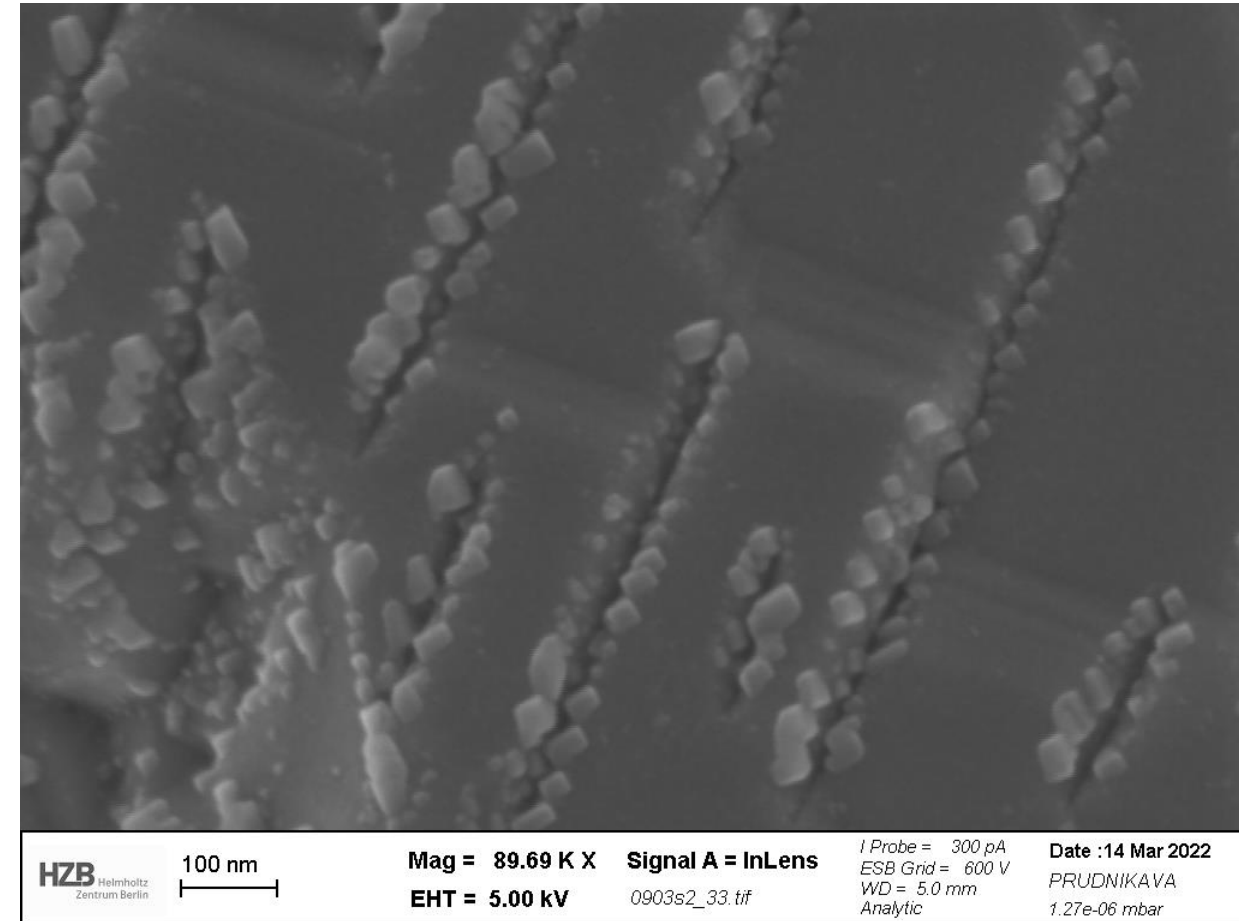
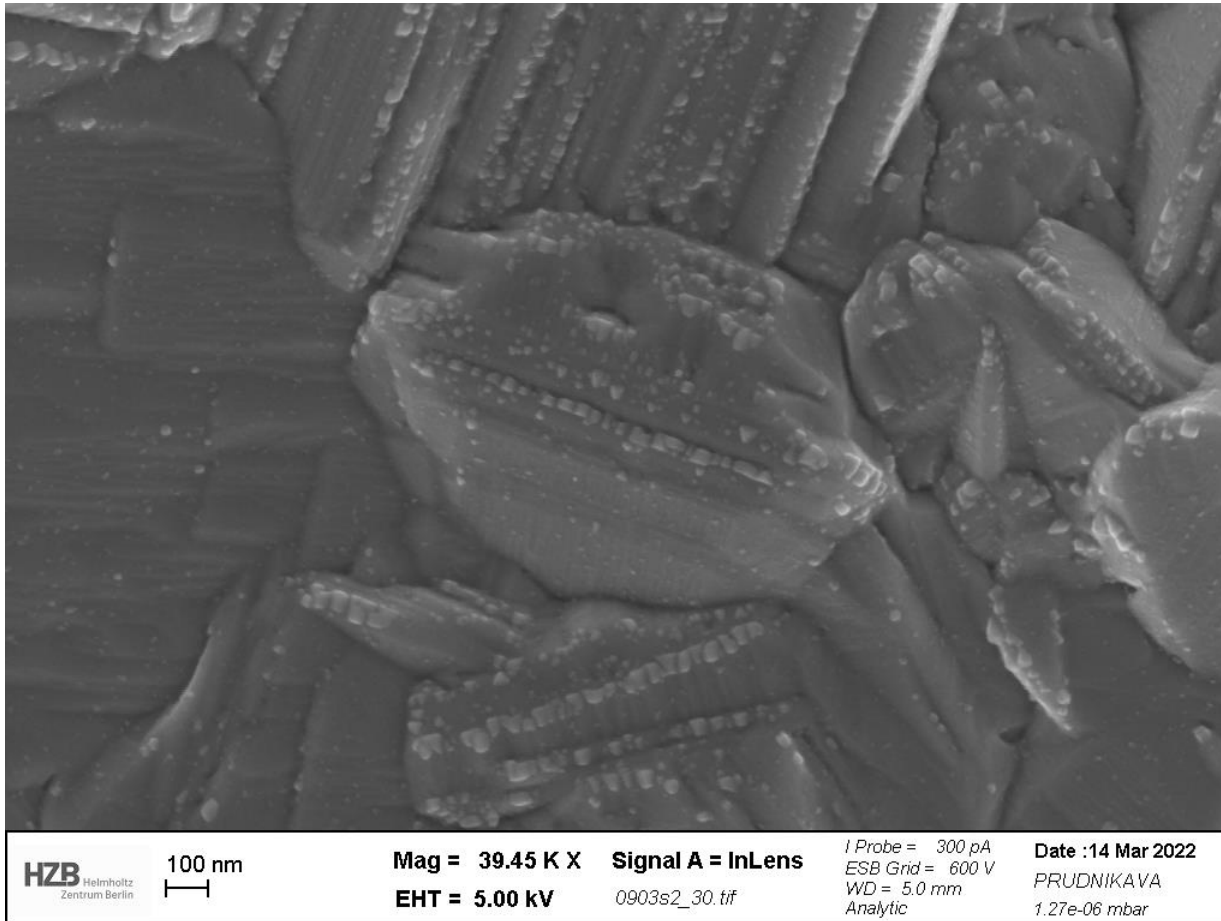


80 mA (without MPS)



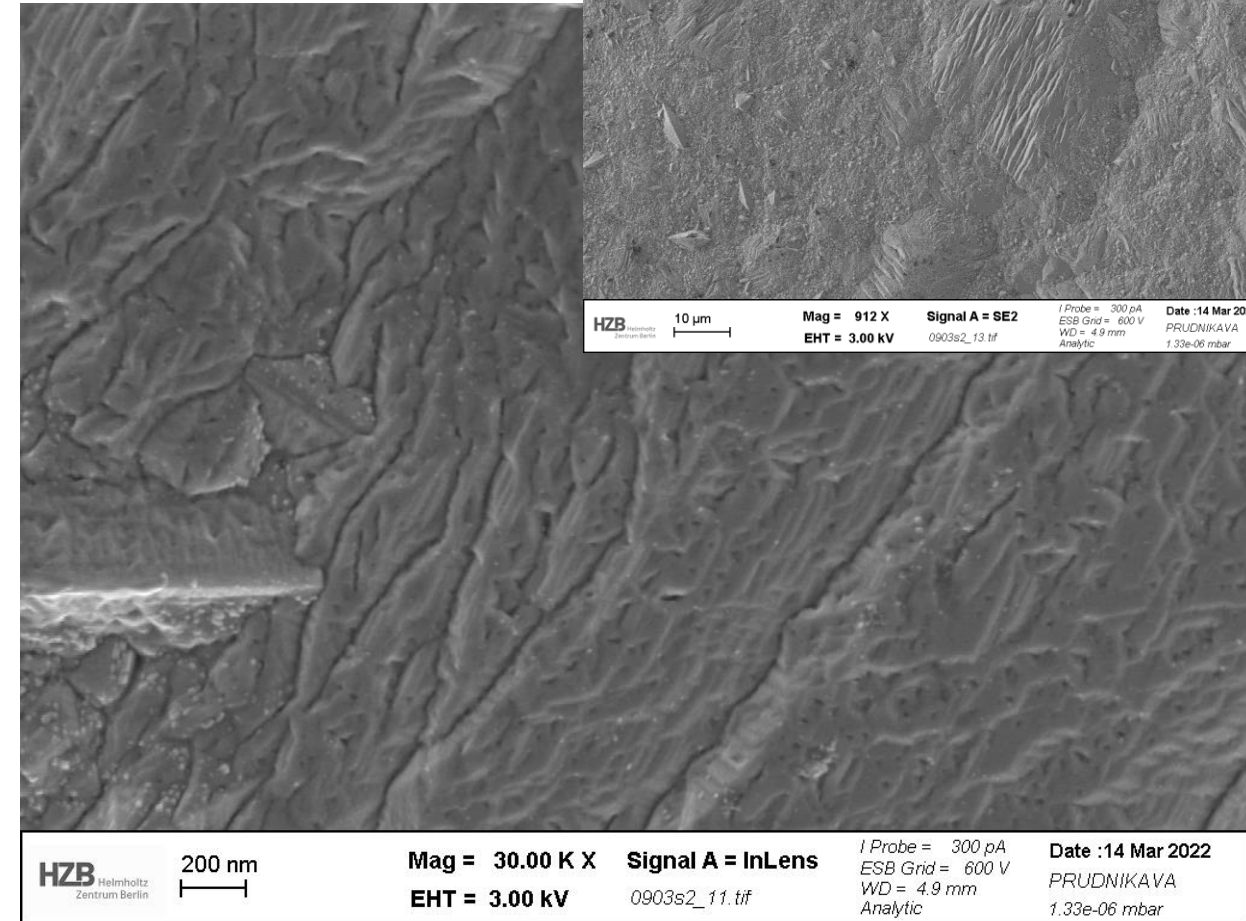
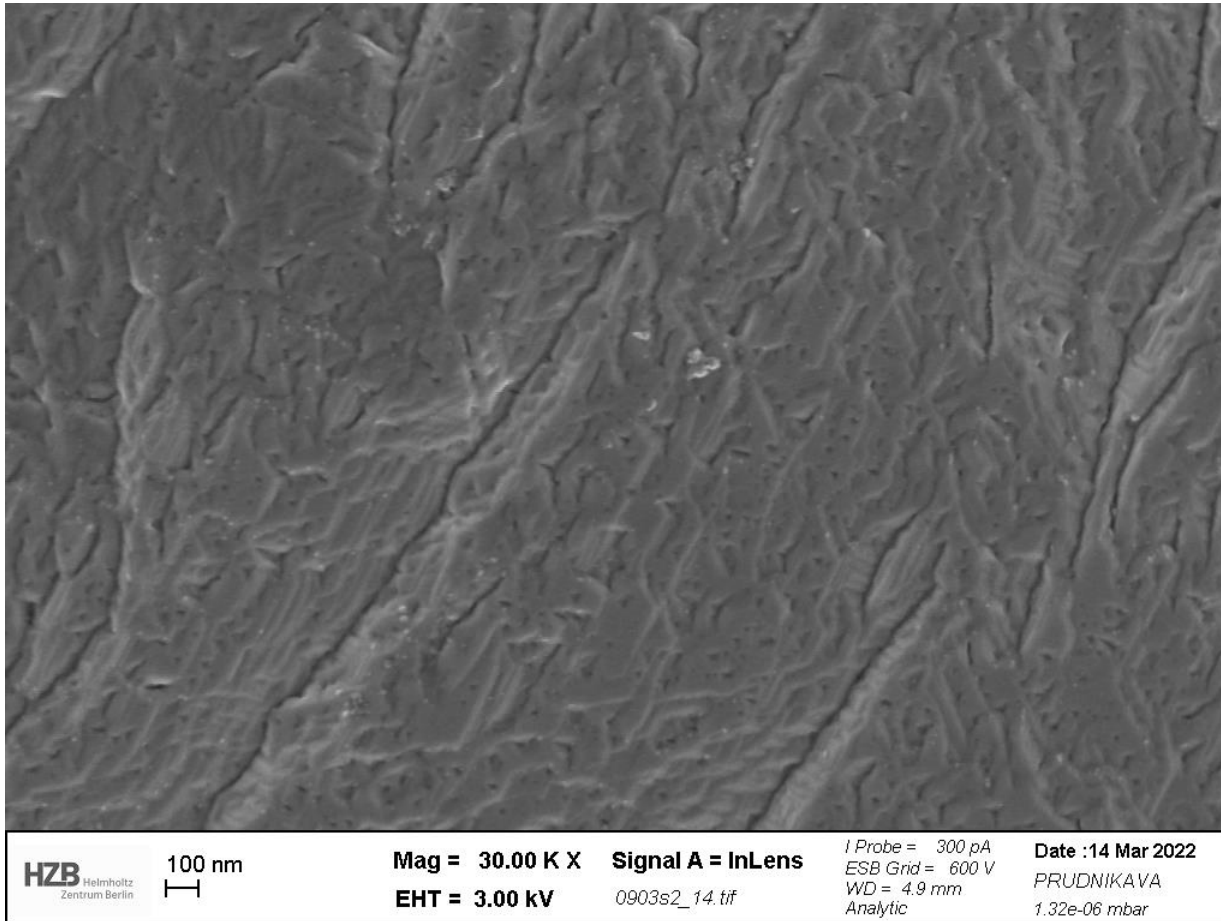
no visible oxidation

some crystal planes reveal oxide particles



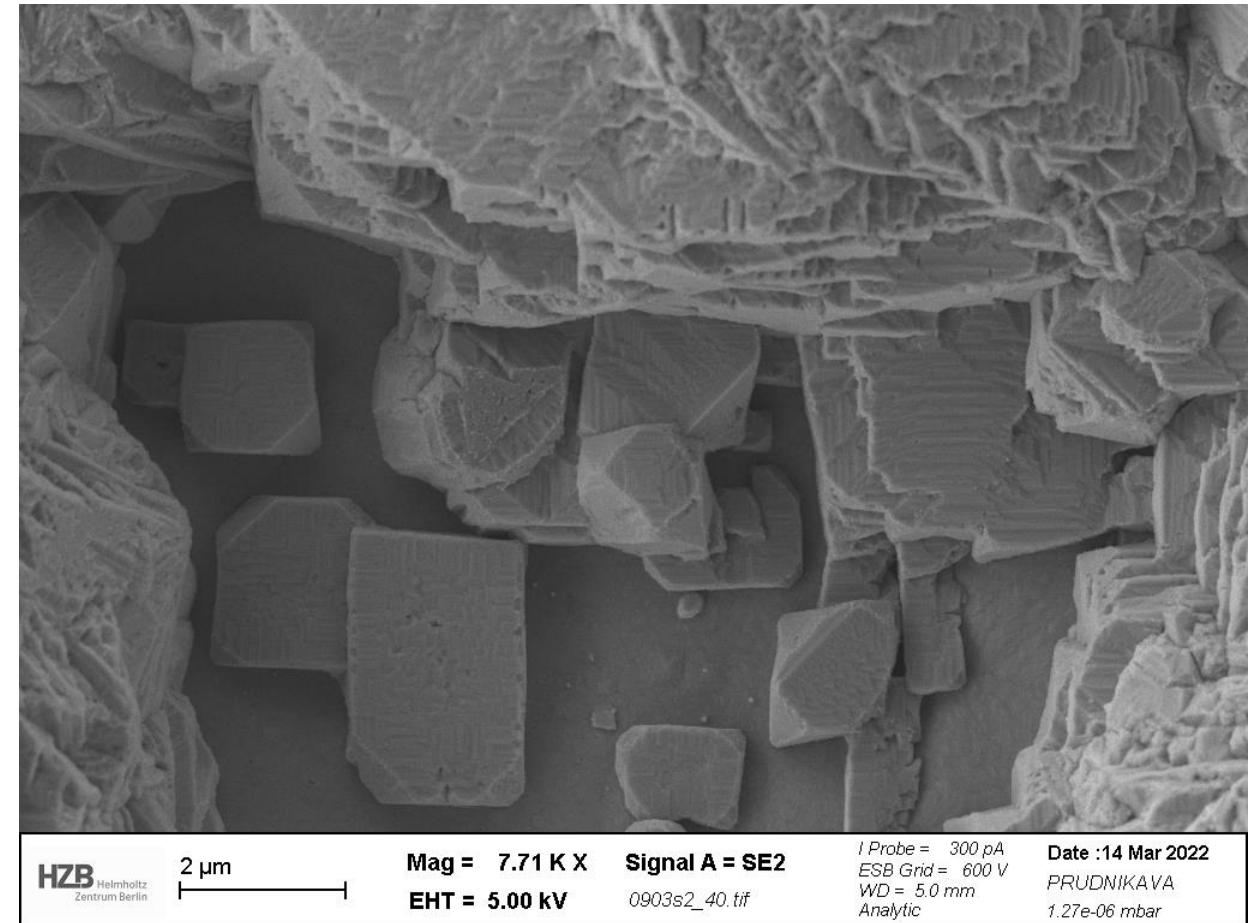
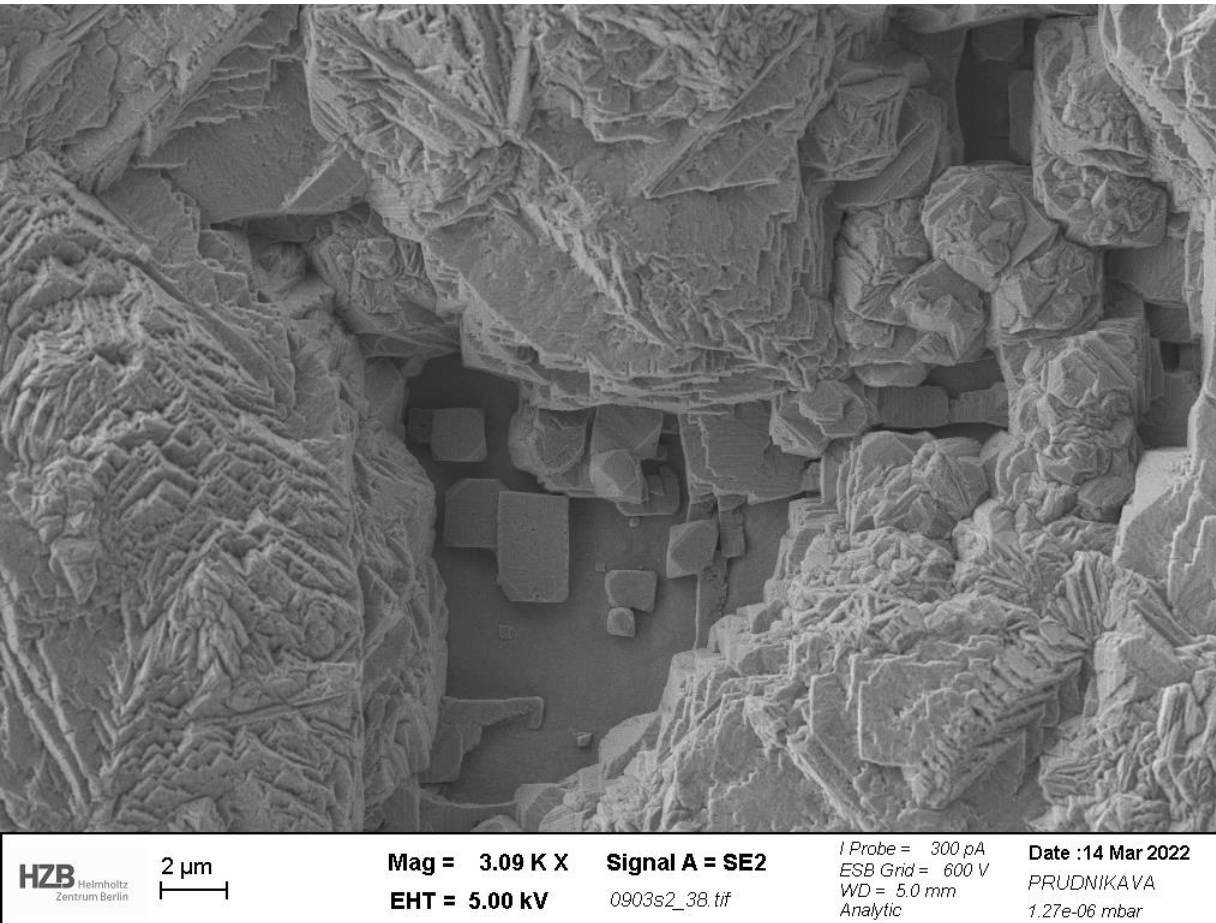
Sample 2 (50 mA, no MPS)

some - do not..

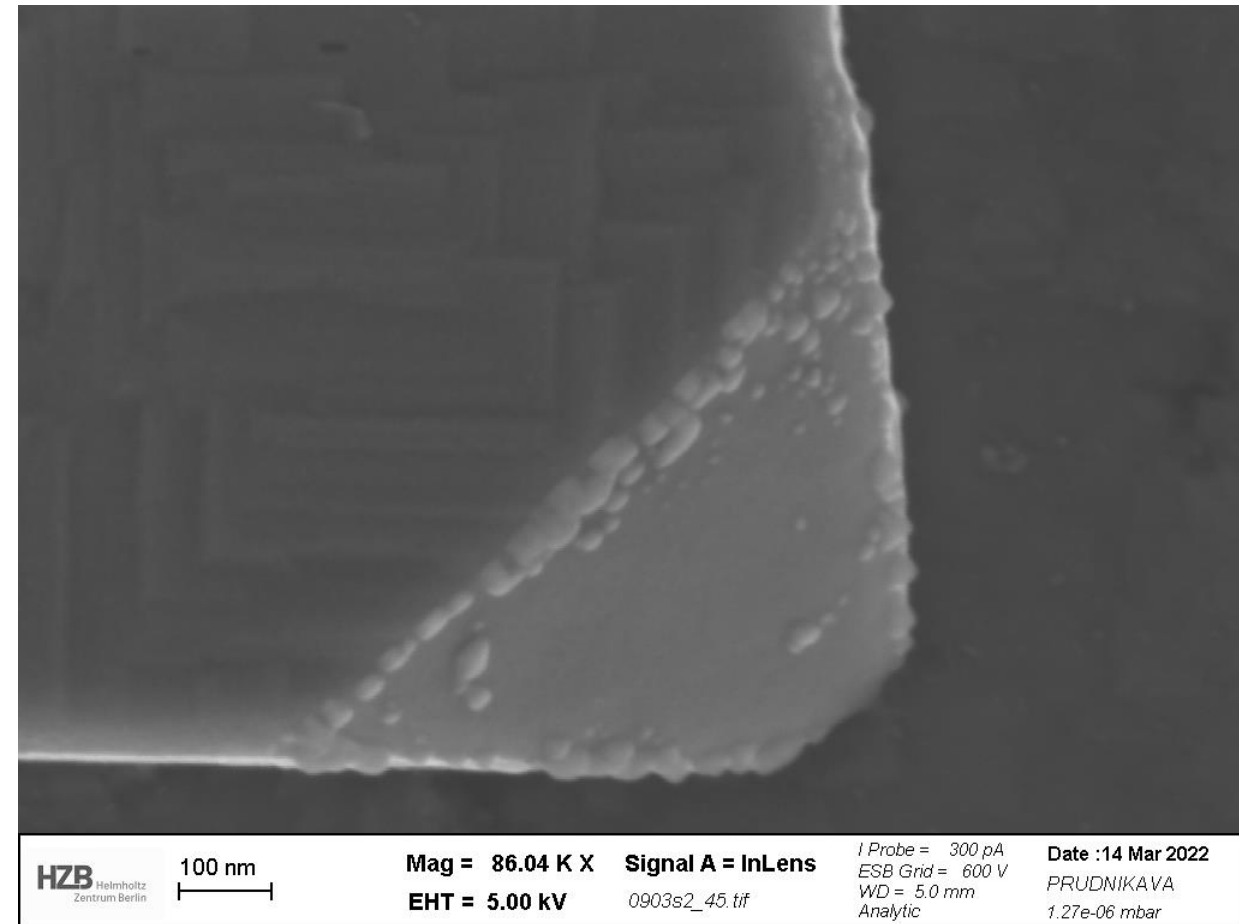
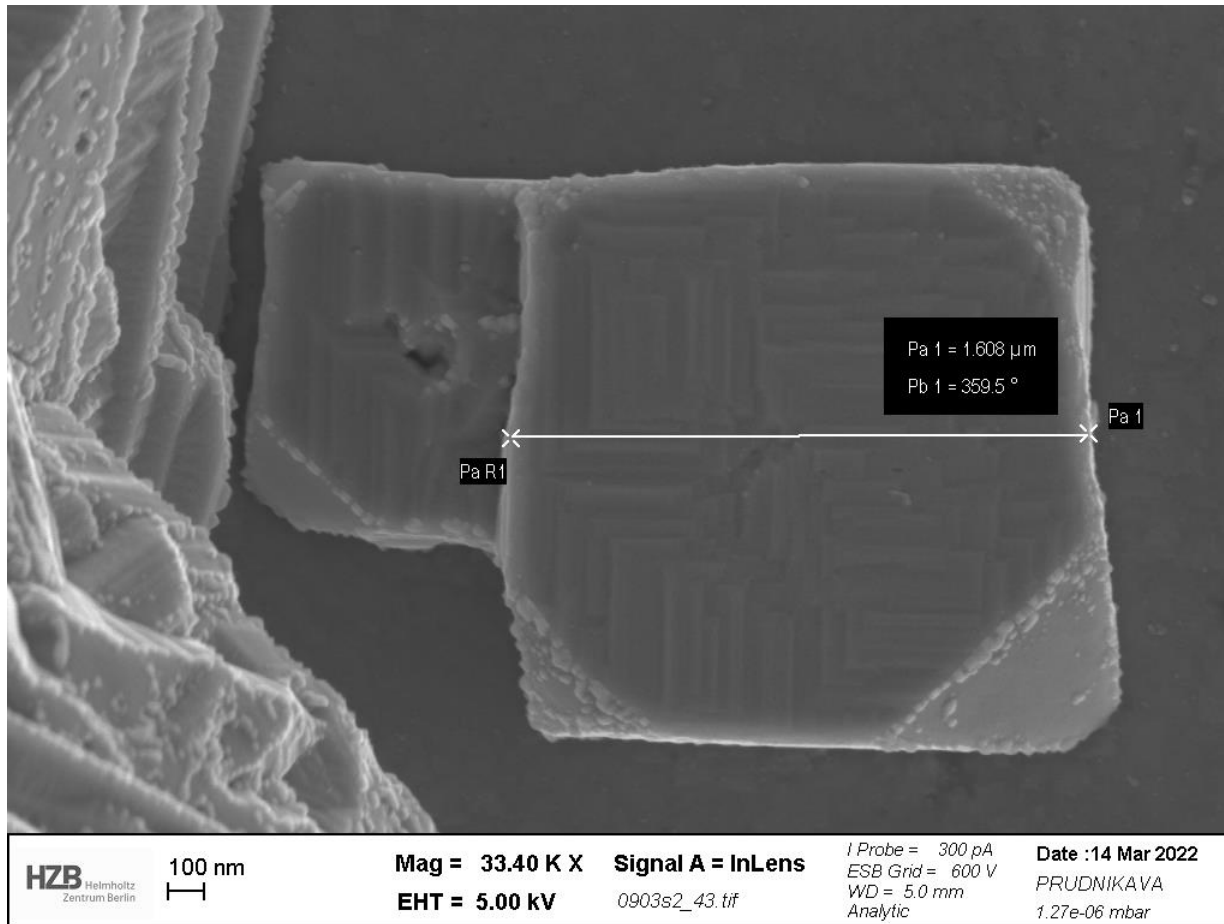


Sample 2 (50 mA, no MPS)

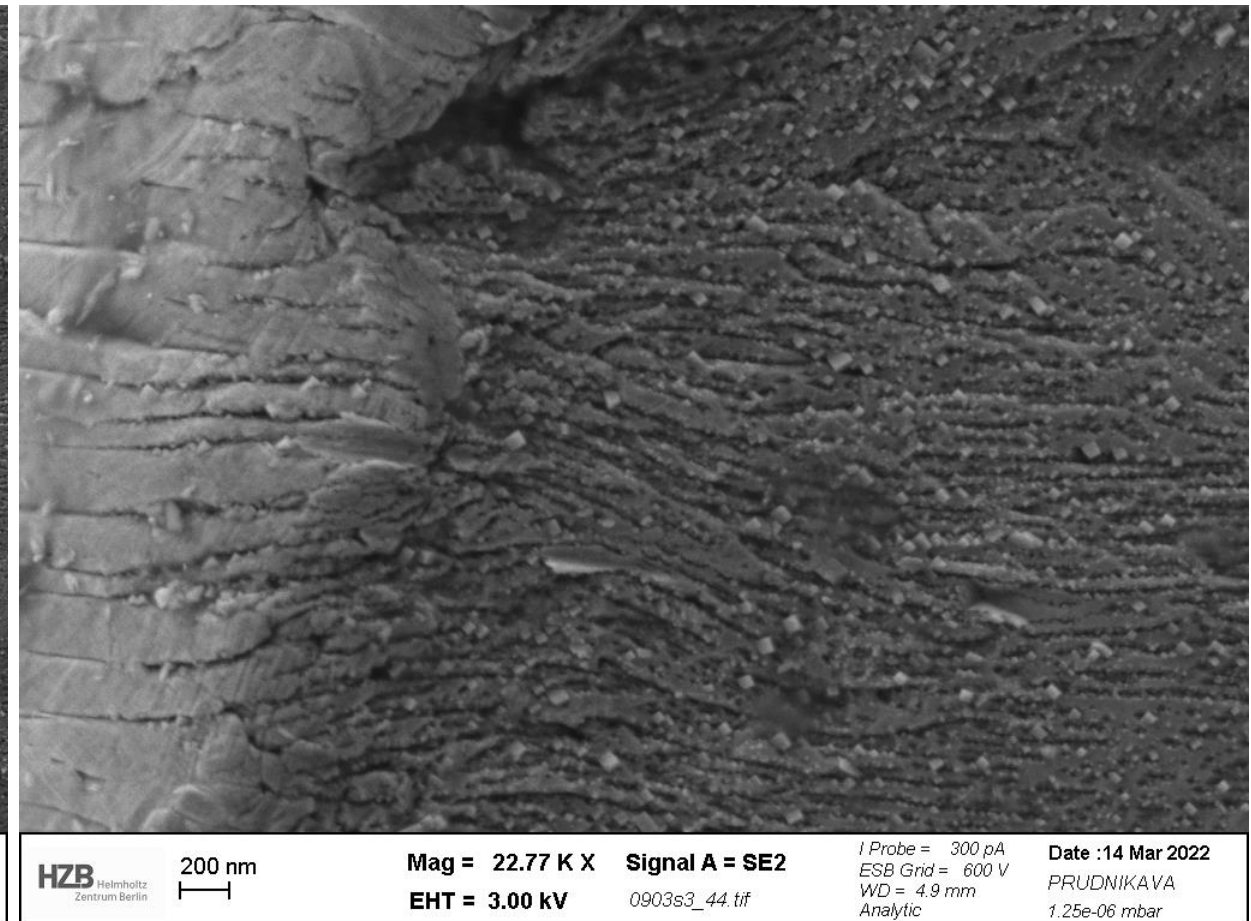
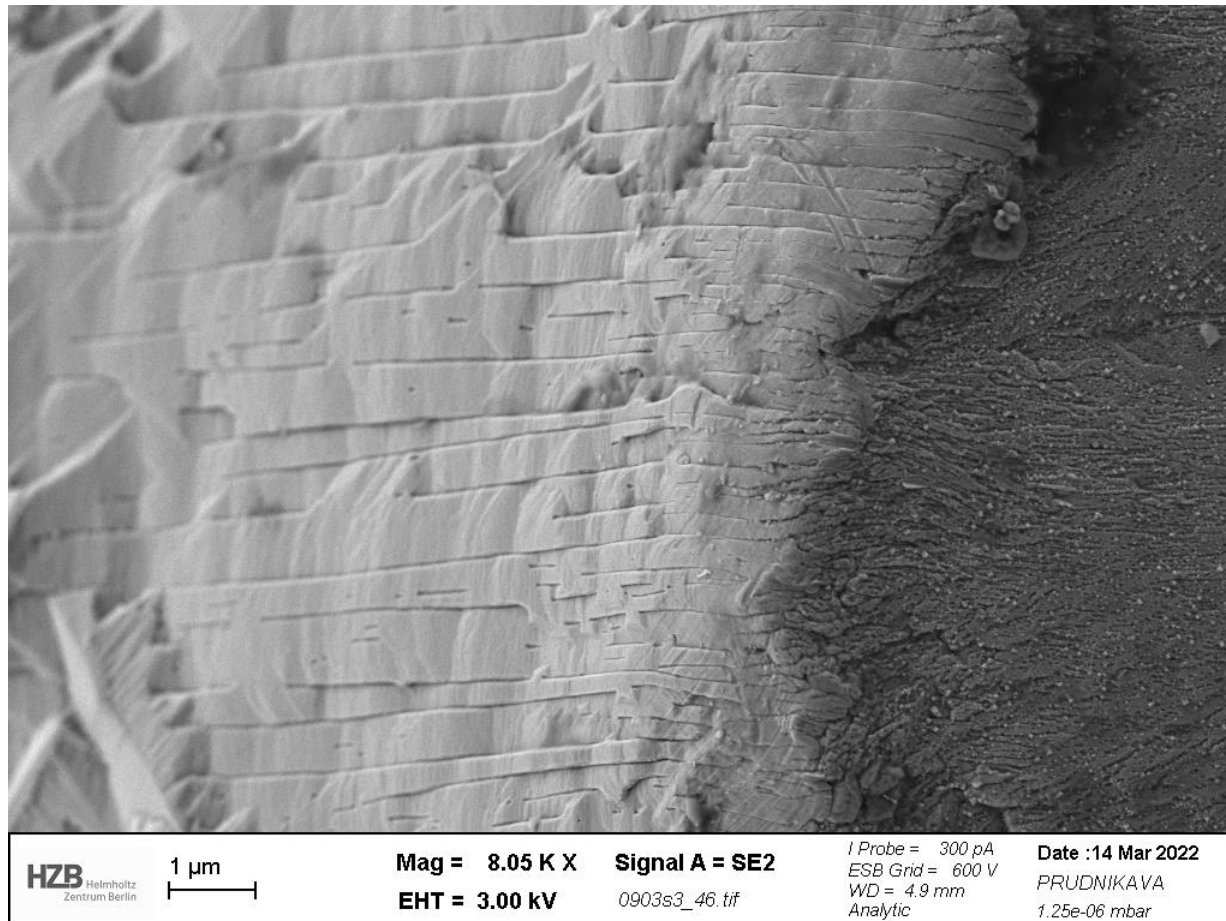
Testing Acidic Electrolytes (2): Cu plating onto Copper



Testing Acidic Electrolytes (2): Cu plating onto Copper

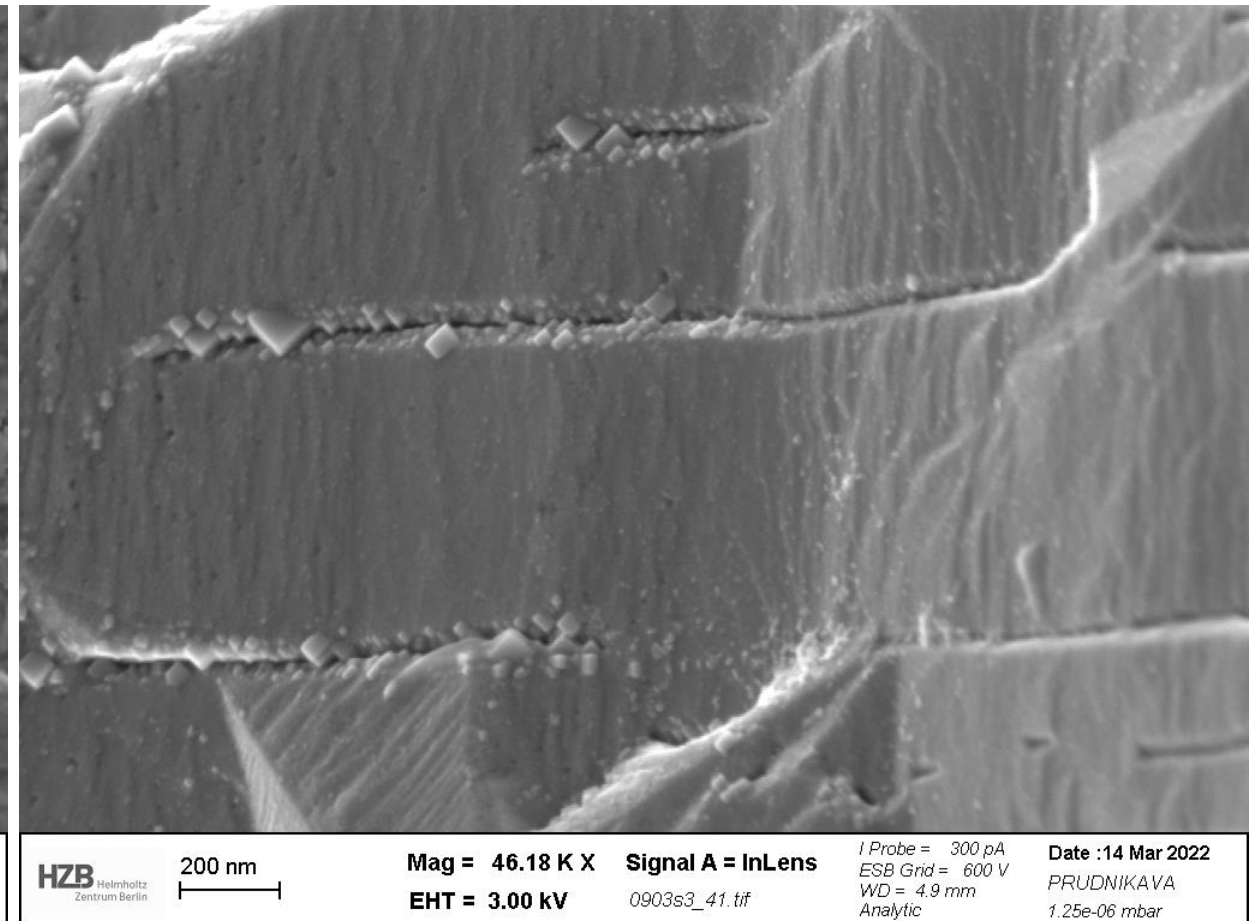
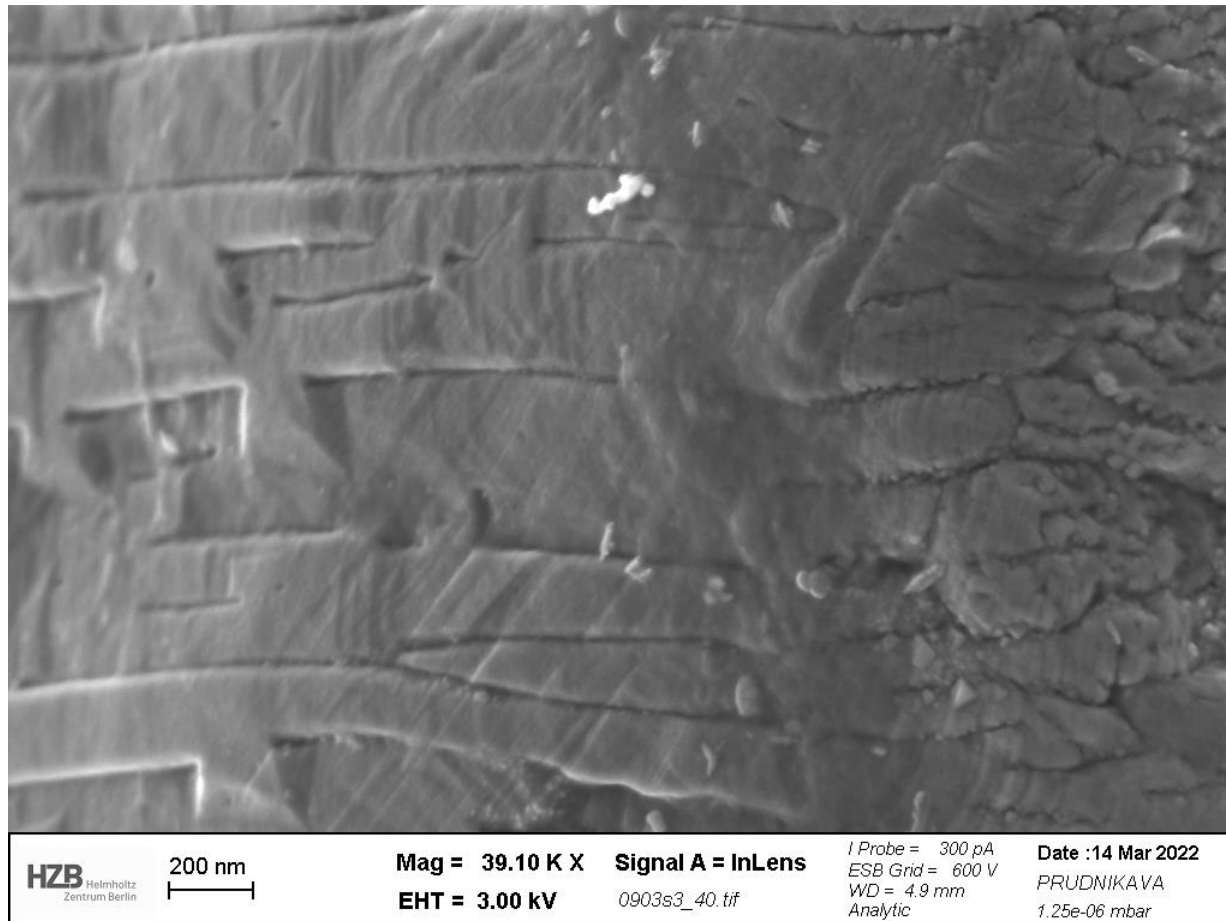


continuous growth of the Cu grain along one crystallographic direction



Sample 3 (50 mA, MPS)

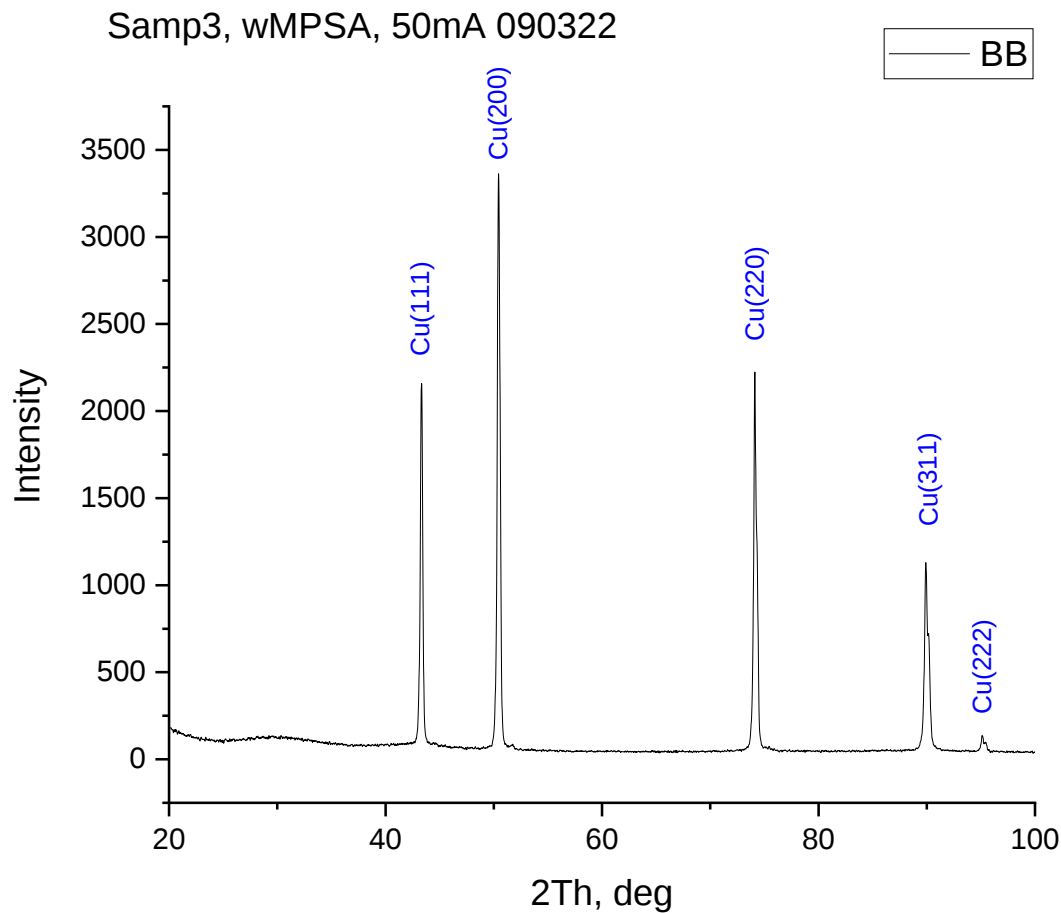
continuous growth of the Cu grain along one crystallographic direction



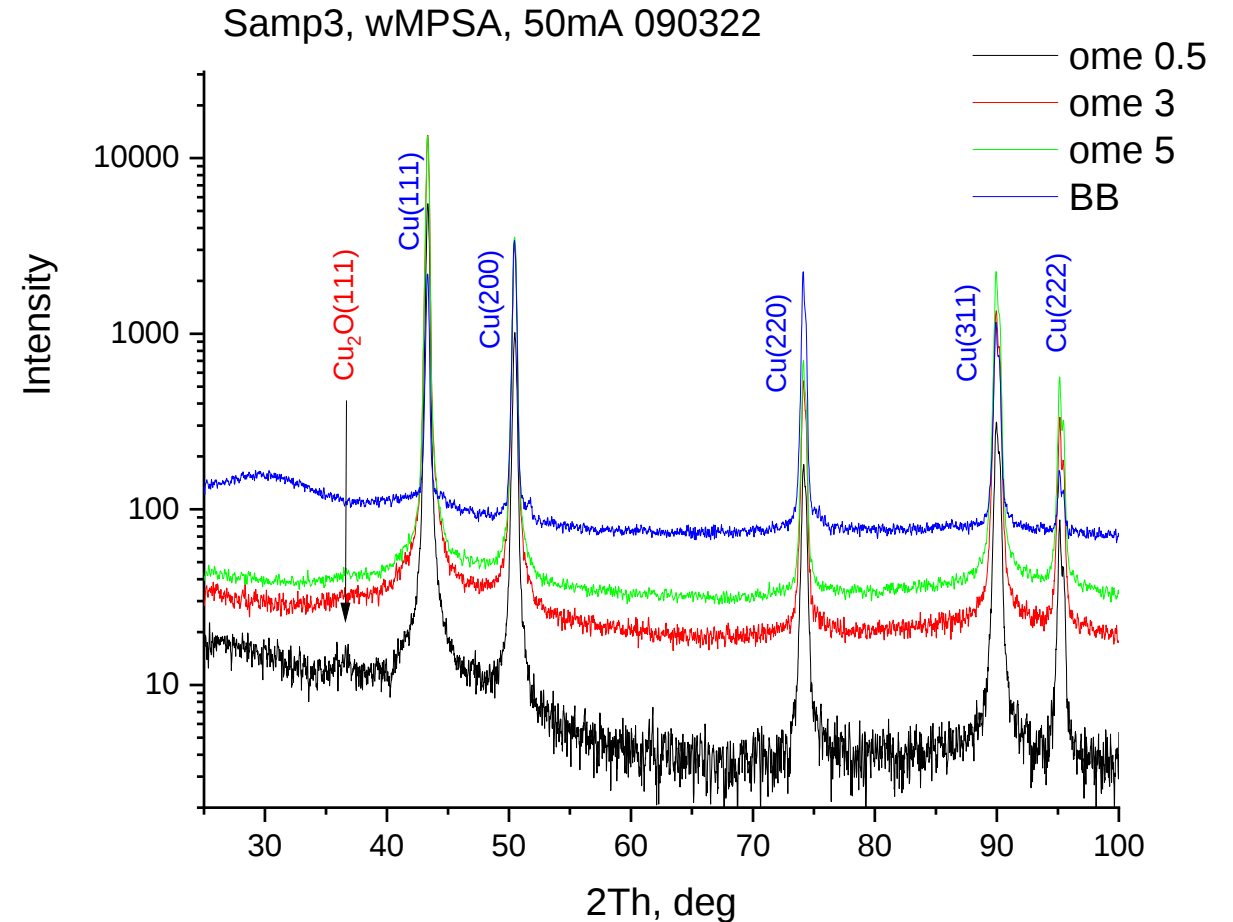
Sample 3 (50 mA, MPS)

80 mA (with MPS)

Cryst. Size 33.40 nm



Cu(200) is the preferential
crystal growth plane



Possible origins of the topographic pattern of Cu-film:

1. Rough Cu-electrode surface after chemical etching => changed Cu-seed layer precipitation behavior
2. Relatively low electrolyte bath temperature (17-8C as compared to the best results at 30-35°C)

Possible origins of the topographic pattern of Cu-film:

	1.	2.
1. no	Cu-plating onto smooth Cu	Cu-plating at 30°C onto smooth Cu
2. no	Sample 1 80 mA, 17-18 ° C	Sample 2 80 mA, 30-32°C

$\text{CuSO}_4 \cdot 5\text{H}_2\text{O}$
 H_2SO_4
 H_2O
additives:

- NaCl
- Janus Green B
- MPS

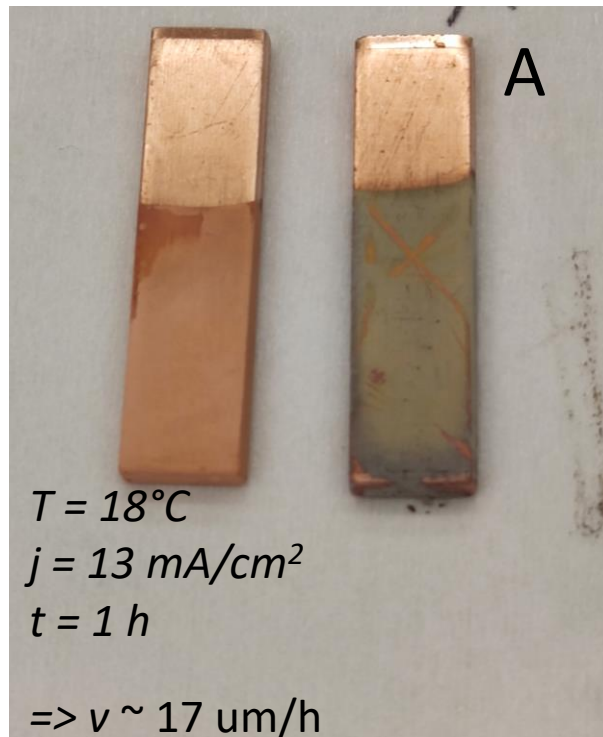


deposition rate: $v=20.2 \text{ um/h}$

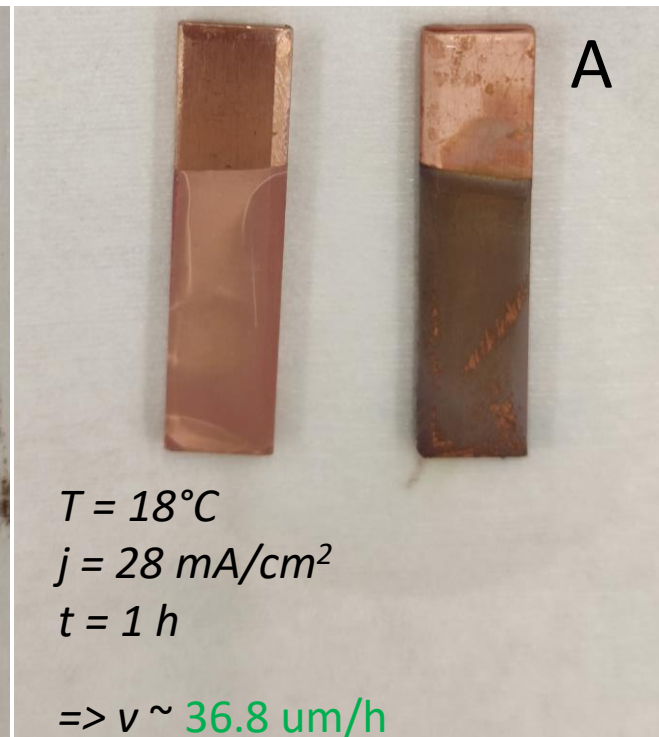
$v=18.6 \text{ um/h}$

Electrolyte: High speed bright copper electroplating solution by Sigma Aldrich (up to 5 $\mu\text{m}/\text{min}$)

80 mA



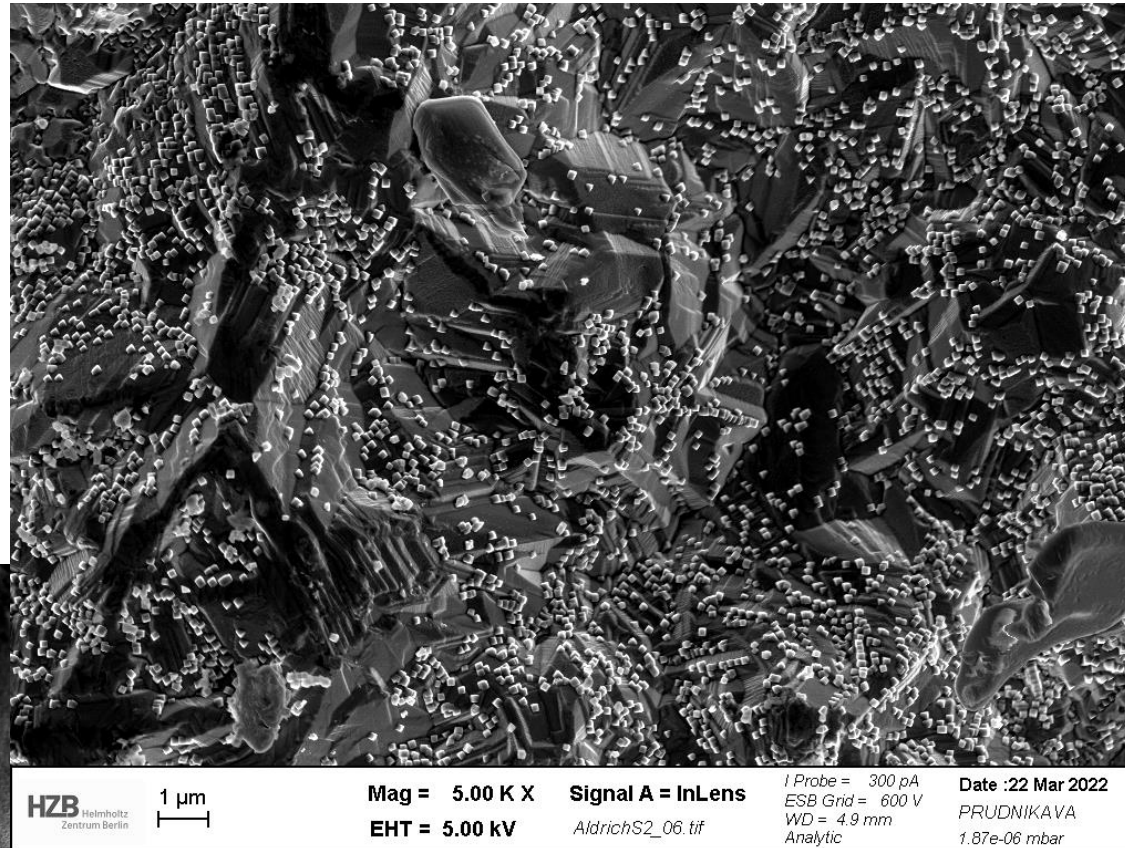
200 mA



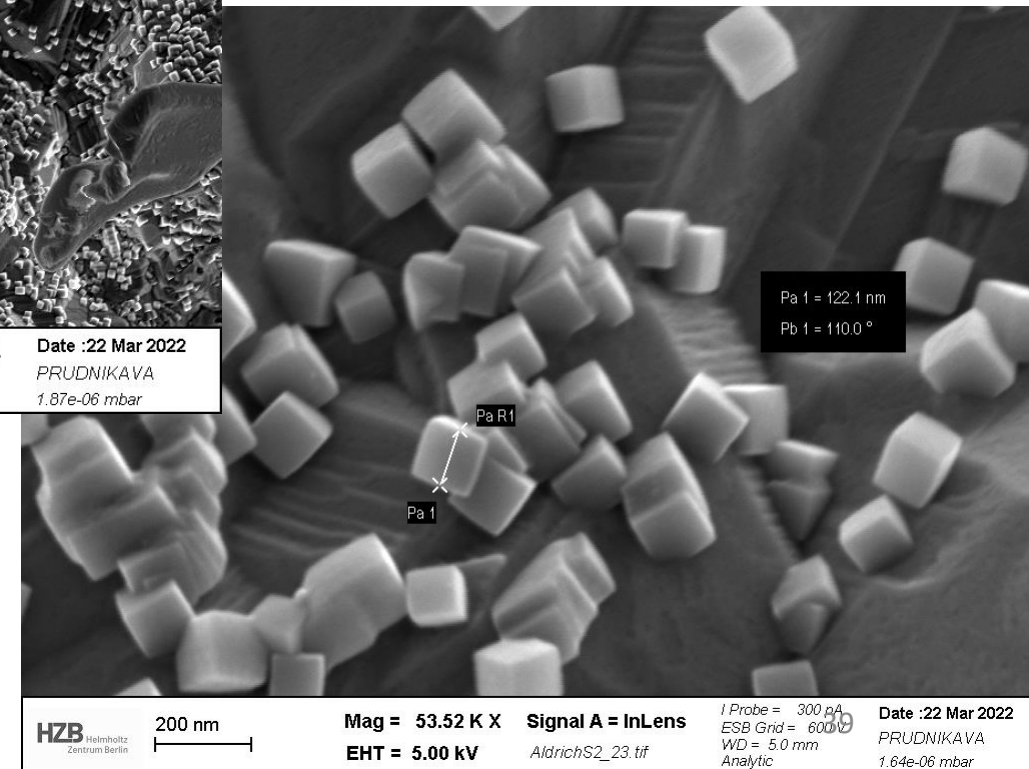
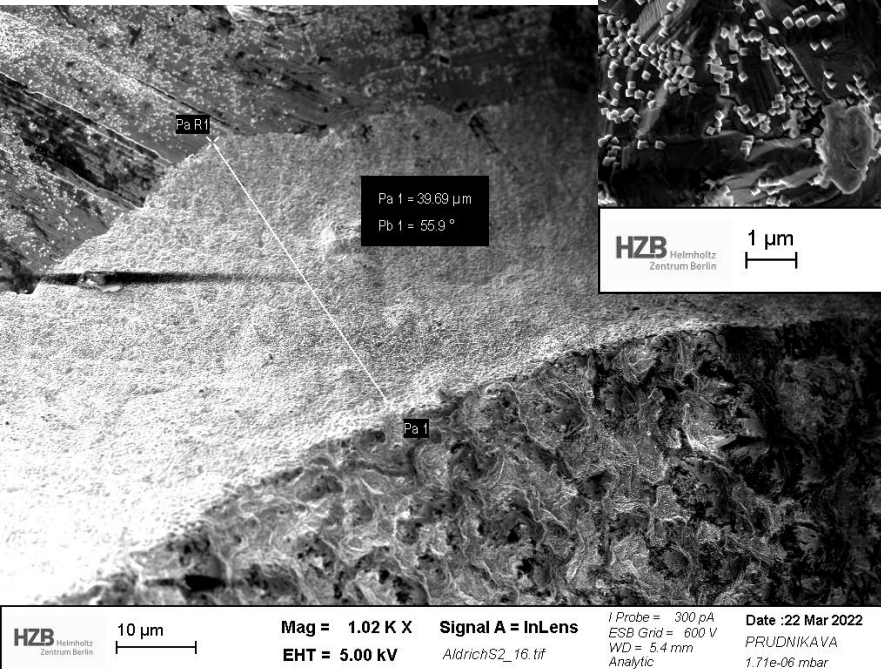
- **Anode degradation** (even if a decreased current densities are applied to Anode)

Cu-film

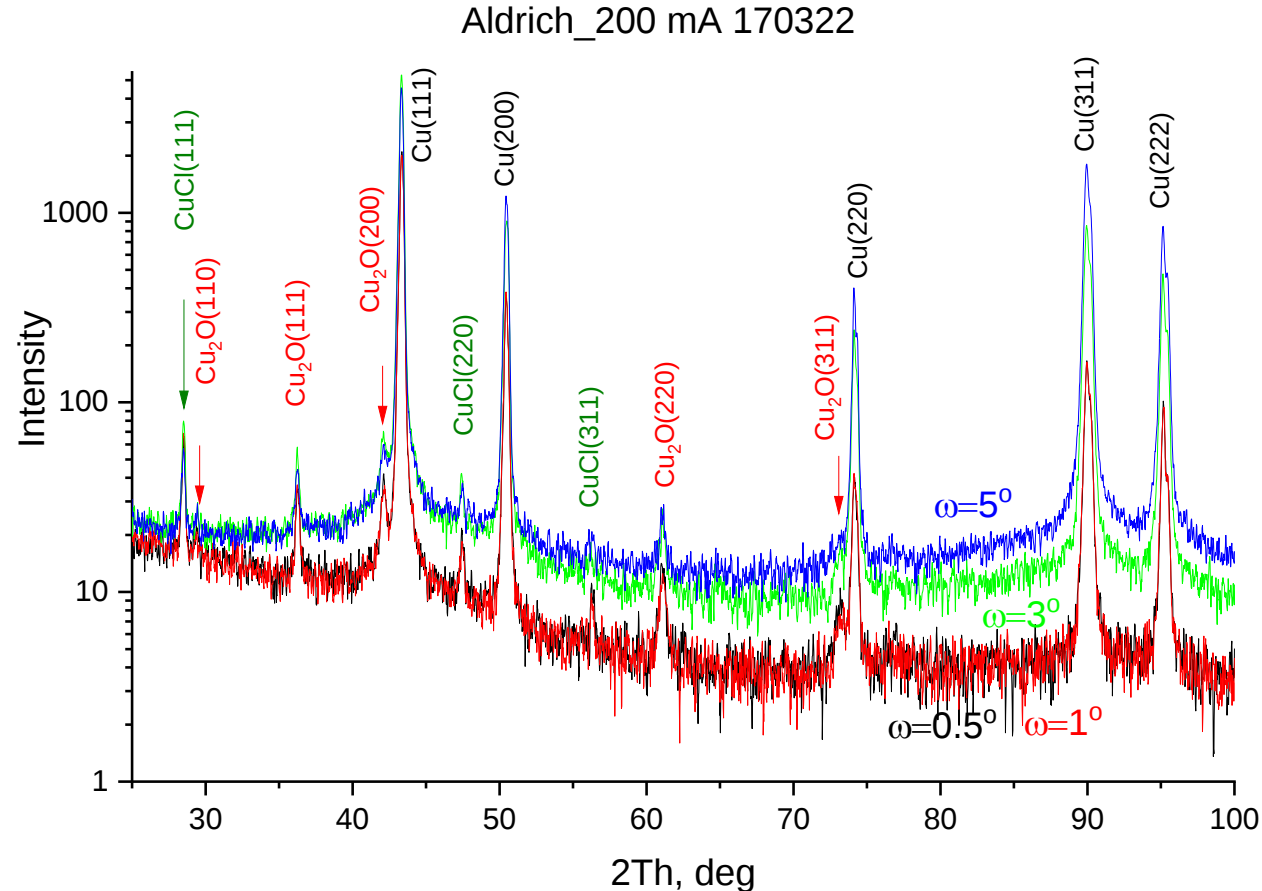
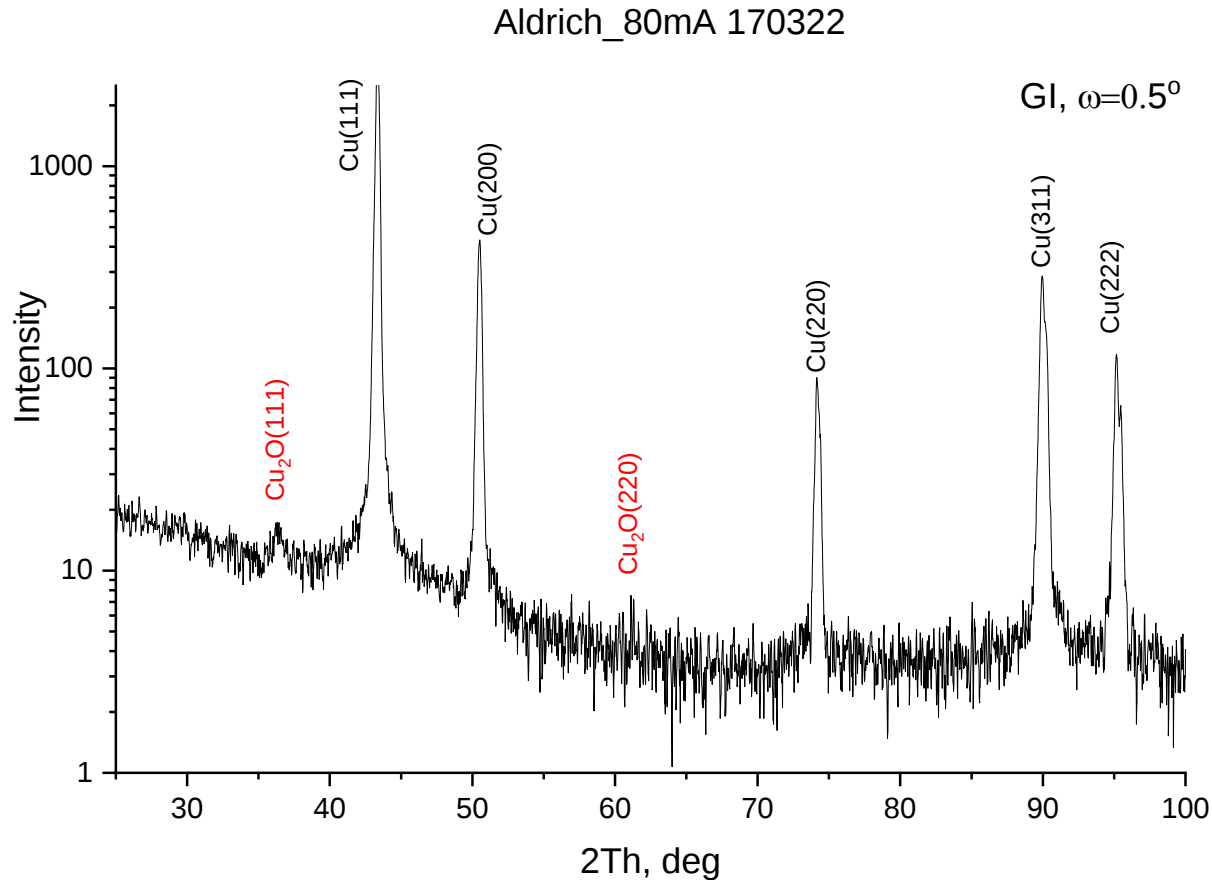
Sigma Aldrich, 200 mA



Cu-film oxidation (larger particles as compared to other samples)



XRD: Cu films

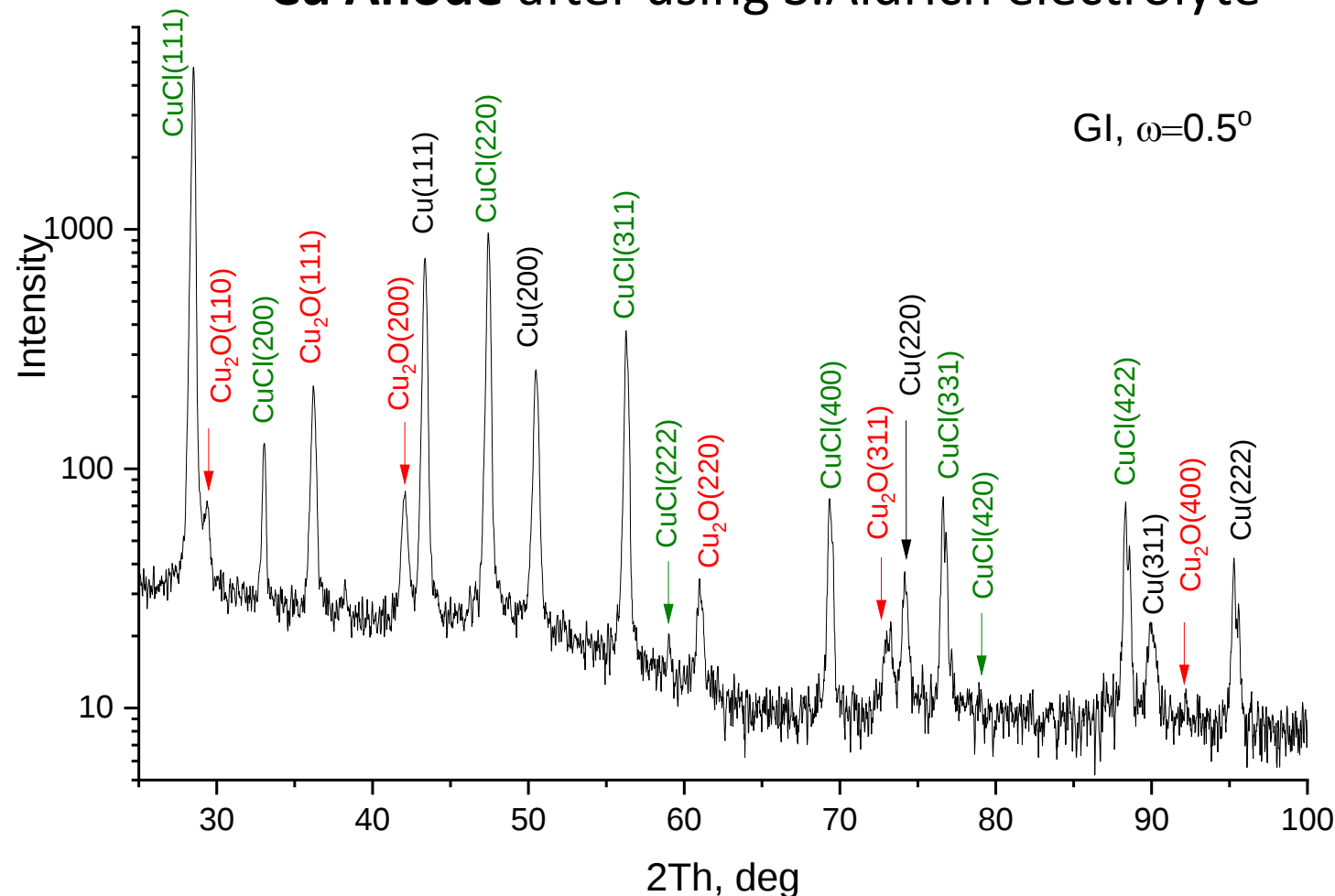


cubic Cu_2O and CuCl are present

$\Leftrightarrow$ related to Anode problem?

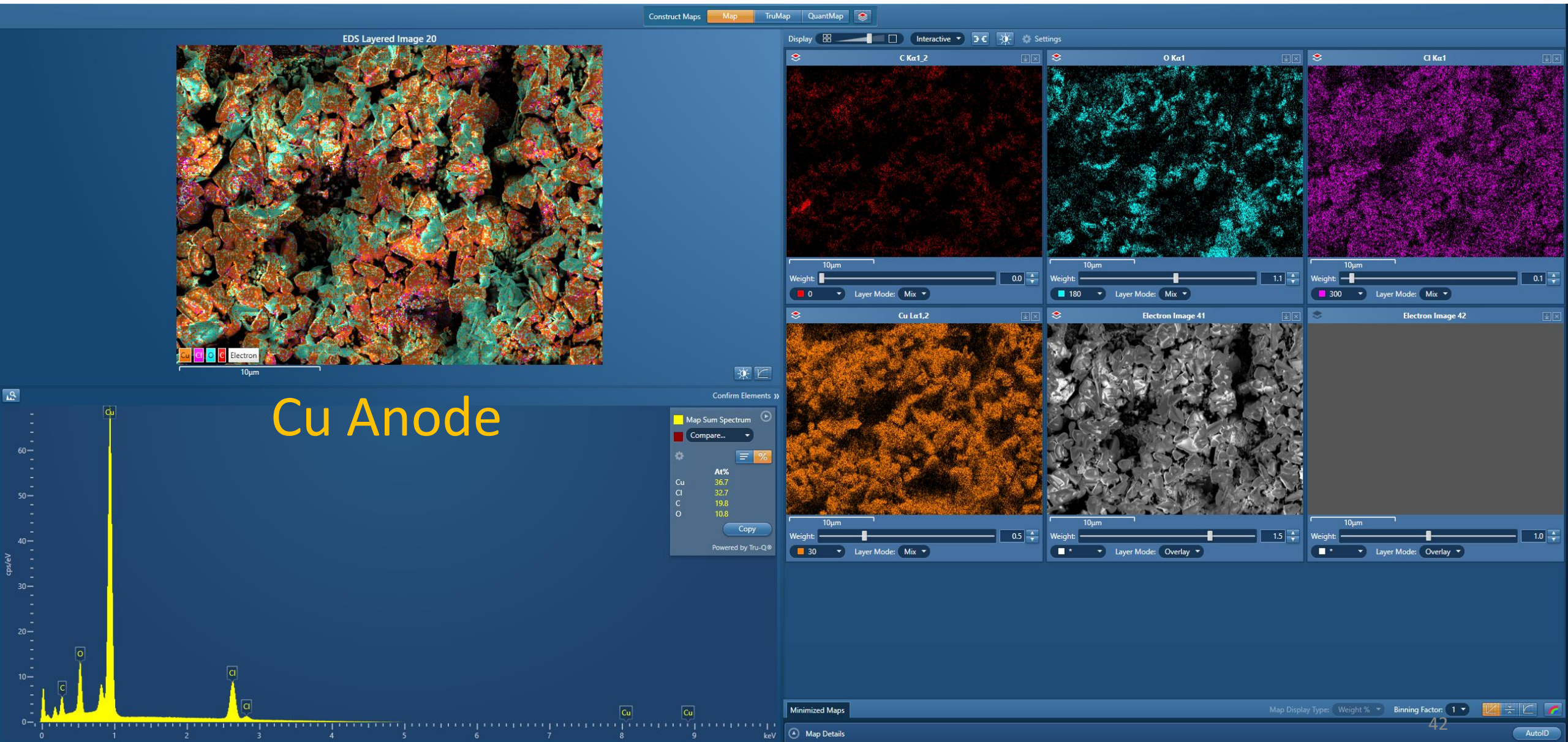
XRD: Cu Anode

Cu Anode after using S.Aldrich electrolyte

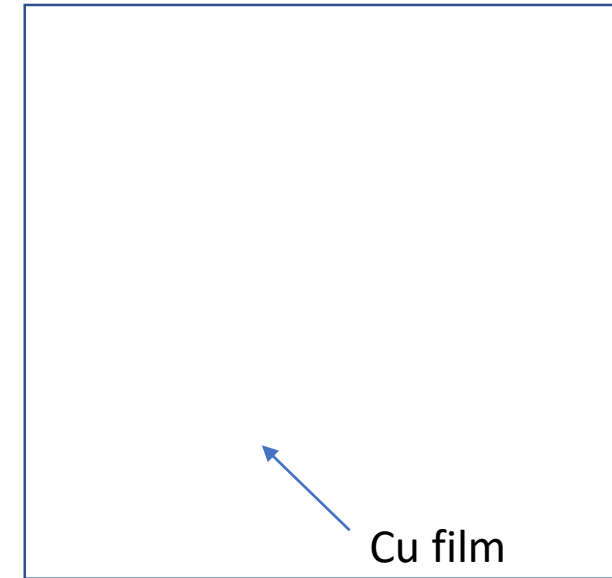


⇒ Glassy Carbon Anode
to be tested

Testing Acidic Electrolytes (3): Cu Anode



- Procedure for direct plating of Cu onto Nb developed (“buffer layer”). Thin Cu-film was possible to produce (~170 nm). Scotch-tape and liquid nitrogen tested. To be used as a buffer layer, it’s thickness to be increased to 3-5 μm .
- Several types of hi-speed Cu-plating baths have been investigated. The plating parameters providing deposition rates up to 37 $\mu\text{m}/\text{h}$ and surface-oxide-free Cu-films have been demonstrated (yet 25 $\mu\text{m}/\text{h}$).
- **Ongoing:**
 - Patent preparation for the Cu/Nb thin film recipe;
 - building up the thickness of “the buffer Cu layer”;
 - the commercial conductivity meters for Cu (at RT) to be tested
 - preparing the four-probe conductivity test setup for cryo-T (Y. Tamashevich)
 - creating Cu/Cu/Nb structure



Electrolyte after 2.5 months storage reproduced the results on Cu-plating of Niobium
=> **Stable solution!**

Newly prepared electrolyte worked as well for Niobium
=> **reproducible results**